

Cite this: *J. Mater. Chem. A*, 2021, 9, 19554Received 16th May 2021  
Accepted 22nd July 2021

DOI: 10.1039/d1ta04130d

rsc.li/materials-a

# Advances in SnO<sub>2</sub>-based perovskite solar cells: from preparation to photovoltaic applications

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Perovskite solar cells (PSCs) have recently demonstrated a rapid power conversion efficiency of above 25%. In terms of physical properties, SnO<sub>2</sub> is similar to TiO<sub>2</sub> but with stronger charge extraction at the interface. Furthermore, the SnO<sub>2</sub> electron transporting layer (ETL) is prepared using new, simple, and efficient methods, resulting in high-performance PSCs. This review initially described recent progress in SnO<sub>2</sub> nanostructures and preparation methods. The passivation options were then divided into elemental doping, bilayer alterations, and interfacial modifications. Finally, we discussed the challenges and limitations of SnO<sub>2</sub> ETL-based PSCs and made recommendations for further research.

## 1. Introduction

Nowadays, perovskite solar cells (PSCs) have attracted substantial attention due to low expense, facile production, and high power conversion efficiency (PCE).<sup>1–5</sup> Besides, the rapid development of theoretical and practical research has boosted its PCE from 3.8%<sup>6</sup> to 25.5%<sup>3,7–12</sup> in just ten years, which is close to that of polycrystalline silicon solar energy cells (Fig. 1a).

The general chemical formula of perovskite is ABX<sub>3</sub>, in which A involves an organic cation group or inorganic metal cations such as Methylammonium (CH<sub>3</sub>NH<sub>3</sub><sup>+</sup>), formamidinium (NH<sub>2</sub>CH=NH<sub>2</sub><sup>+</sup>), as well as cesium (Cs<sup>+</sup>); B is generally a heavy metal cation such as lead(II) (Pb<sup>2+</sup>) and tin(II) (Sn<sup>2+</sup>); X is

commonly a halide ion including chlorine (Cl<sup>−</sup>), bromide (Br<sup>−</sup>), or iodine (I<sup>−</sup>).<sup>13,14</sup> (Fig. 1b) The Goldschmidt tolerance factor (*t*),<sup>15</sup> is a simple way to check whether or not specific compositions can form a stable perovskite structure.

$$t = \frac{r_A + r_X}{\sqrt{2}(r_B + r_X)}$$

where *r*<sub>A</sub>, *r*<sub>B</sub>, and *r*<sub>X</sub> represent the corresponding ionic radius of A, B and X, respectively. The 3D perovskite structure can be stable only when *t* is located in the range of ~0.8–1.0.<sup>16</sup>

PSC structures are always classified into two types: n-i-p structures and p-i-n structures. The n-i-p structures are of two types: n-i-p mesoporous and n-i-p planar structures, whereas the p-i-n structures are only p-i-n planar structures (Fig. 1c–e).<sup>4,17,18</sup> The n-i-p mesoporous structures are usually composed of a transparent conductive electrode such as fluorine-doped tin oxide (FTO) and indium tin oxide (ITO), an electron transporting layer (ETL), a mesoporous scaffold layer (which is

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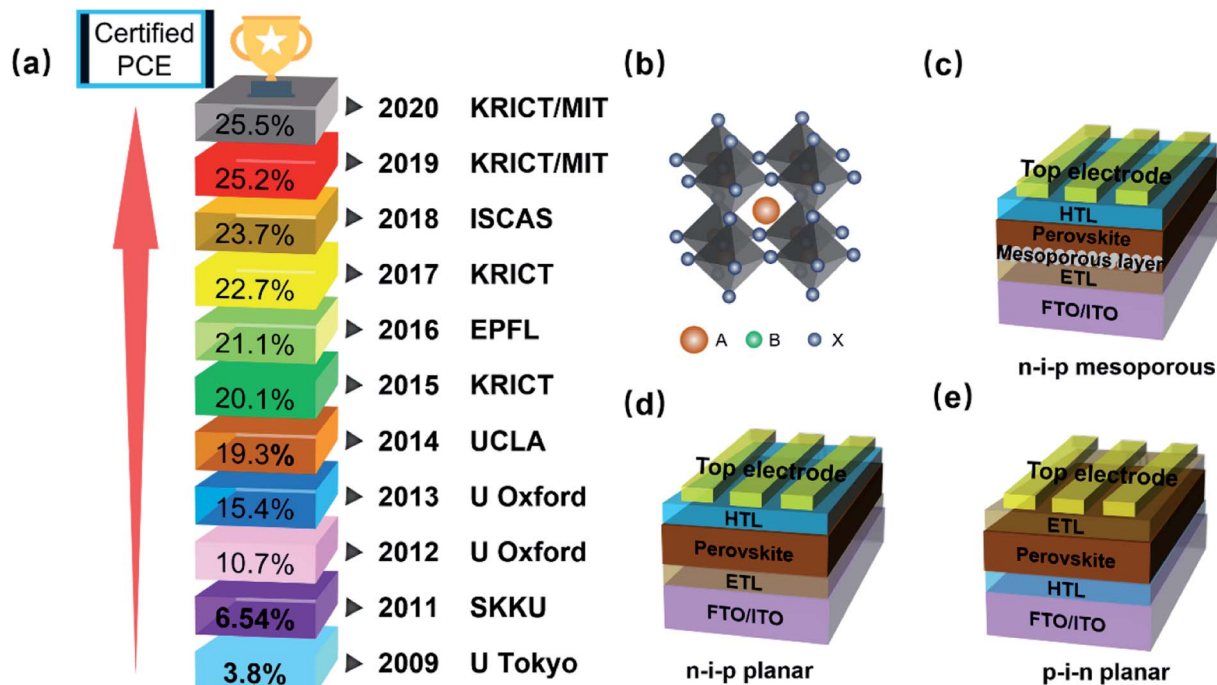


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**Fig. 1** (a) Brief development history of PSCs (2009,<sup>6</sup> 2011,<sup>28</sup> 2012,<sup>29</sup> 2013,<sup>30</sup> 2014,<sup>31</sup> 2015,<sup>32</sup> 2016,<sup>33</sup> 2017,<sup>34</sup> 2018,<sup>35</sup> 2019,<sup>36</sup> and 2020,<sup>7</sup>). (b) Crystal structure of cubic for metal halide perovskite. (c) PSCs with an n-i-p mesoporous structure. (d) PSCs with a regular n-i-p planar structure. (e) PSCs with a p-i-n planar structure.

always TiO<sub>2</sub> or Al<sub>2</sub>O<sub>3</sub>), a perovskite absorption layer, a hole transporting layer (HTL) and a top electrode. However, the TiO<sub>2</sub> mesoporous layer is always post-treated at high temperatures (typically above 450 °C) to increase the conductivity and remove the organic material.<sup>19–25</sup> By contrast, the planar structure of n-i-p PSCs without a mesoporous scaffold also achieves a similar efficient power output and long-term stability to the device with the mesoporous configuration.<sup>26,27</sup>

TiO<sub>2</sub> is a widely utilized ETL in PSCs for n-i-p planar structures due to its proper bandgap and good transmittance.<sup>37–40</sup> However, when tested under continuous light illumination, TiO<sub>2</sub> obtains electrons from I<sup>–</sup>, leading to perovskite cubic structural damage and generation of I<sub>2</sub>.<sup>41–43</sup> Furthermore, TiO<sub>2</sub> has a disadvantage of poor electron mobility (10<sup>–5</sup> cm<sup>2</sup> V<sup>–1</sup> s<sup>–1</sup>) due to impaired intrinsic electron mobility (<1 cm<sup>2</sup> V<sup>–1</sup> s<sup>–1</sup>).<sup>44</sup> Furthermore, organic residuals must be removed using high-



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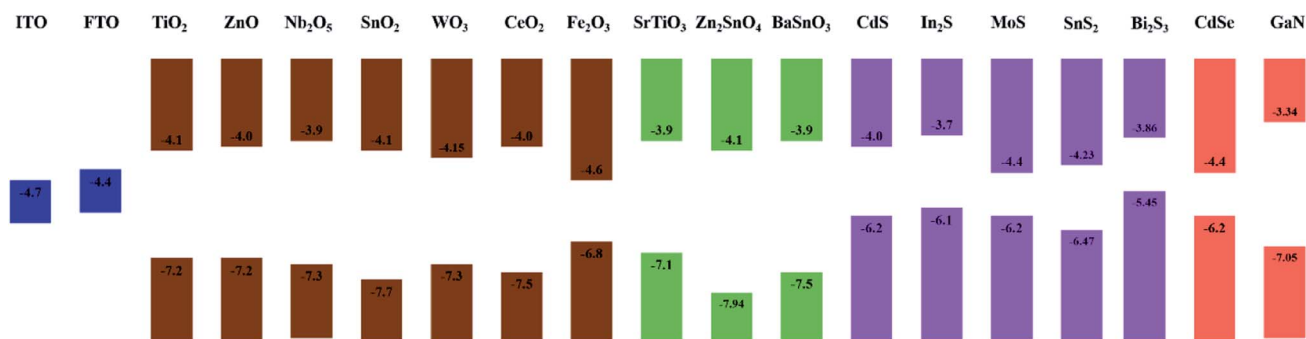


Fig. 2 Conduction band (CB) and valence band (VB) of widely introduced inorganic metal materials as ETLs in PSCs. (blue: metal oxides; green: ternary metal; yellow: metal sulfide; pink: CdSe; and purple: GaN).

temperature procedures, which will take a significant amount of time and energy. For high-performance PSCs, an appropriate and chemically stable ETL is required.

For efficient and stable PSCs, we must adhere to key ETL material principles: (a) high transmittance with minimum optical energy loss, (b) appropriate bandgap matching, (c) high conductivity, (d) low cost and (e) good reproducibility.<sup>45–48</sup> Many metal oxides with unique optical and electrical properties have been reported as potential candidates for replacing TiO<sub>2</sub> (Fig. 2), including metal oxides (ZnO,<sup>49–53</sup> In<sub>2</sub>O<sub>3</sub>,<sup>54</sup> Nb<sub>2</sub>O<sub>5</sub>,<sup>55,56</sup> WO<sub>3</sub>,<sup>57,58</sup> Fe<sub>2</sub>O<sub>3</sub>,<sup>59–62</sup> and CeO<sub>2</sub><sup>63,64</sup>) ternary metal oxides (Zn<sub>2</sub>SnO<sub>4</sub>,<sup>65,66</sup> BaSnO<sub>3</sub>,<sup>67–69</sup> and SrTiO<sub>4</sub><sup>70,71</sup>), metal sulfides (MoS,<sup>72,73</sup> CdS,<sup>74–76</sup> In<sub>2</sub>S,<sup>73</sup> SnS<sub>2</sub><sup>77</sup> and Bi<sub>2</sub>S<sub>3</sub><sup>78</sup>), GaN<sup>79</sup> and CdSe,<sup>80,81</sup> and InGaZnO<sub>4</sub>.<sup>82</sup> However, some drawbacks still exist, like low PCE, poor interfacial contact, or high energy consumption.

Since the first report of 6.5% by Dai *et al.* and the subsequent report of above 15% by Yan *et al.* in 2015,<sup>83,84</sup> the performance of SnO<sub>2</sub>-based PSCs has exceeded 25%, making SnO<sub>2</sub> an appealing ETL in PSCs and is considered a potential alternative instead of TiO<sub>2</sub>. SnO<sub>2</sub> possesses the following remarkable properties: (1) depth CBM and optimal energy level alignment;<sup>85</sup> (2) high bulk electron mobility (significantly greater than TiO<sub>2</sub> ETL) and high conductivity;<sup>86,87</sup> (3) large bandgap (3.6–4.5 eV) and high optical transparency;<sup>88,89</sup> (4) high-temperature flexible deposition; and (5) outstanding stability under light, heat, and moisture, with minimal photoactivity.<sup>90,91</sup> TiO<sub>2</sub> in PSCs usually requires a mesoporous layer and especially high-temperature post-treatment (above 450 °C) to get dense with superior conductivity and crystallinity whether in a spin coating or spraying method, which costs more energy and expense. The SnO<sub>2</sub> ETL is often achieved using spin coating and chemical bath deposition, requiring just post-treatment at low temperatures ( $\leq 200$  °C), which is advantageous for a large-scale preparation.

In this review, we present an overview of the use of SnO<sub>2</sub> in PSCs, including standard preparation procedures, SnO<sub>2</sub> nanostructures, and performance optimization techniques such as elemental doping, surface modifications, and bilayer design. Then, we go into hysteresis and stability issues in further detail. Finally, we explore the problems and limits of SnO<sub>2</sub> ETL-based PSCs, as well as possible future research directions.

## 2. Preparation methods of SnO<sub>2</sub>

The SnO<sub>2</sub> film is typically prepared through solution processing, chemical bath deposition (CBD), and atomic layer deposition (ALD). Recently, emerging methods for deposition of SnO<sub>2</sub> such as e-beam evaporation, magnetron sputtering, and electrochemical deposition are also reported to improve the conformability of SnO<sub>2</sub> for flexible and large-scale PSCs. Fig. 3 shows the schematic illustration of various processing methods for SnO<sub>2</sub> ETLs. We just picked some of the representative data of reported different preparation methods, even though other factors may have an impact on the performance. So, here, we have talked more about performance optimization strategies in detail in Section 4. Aside from these, the PCE is also influenced by the rigid or flexible substrate, preparation environment (N<sub>2</sub> or air), and electrode types.

### 2.1 Solution-processable method

The solution process contains the thermal decomposition method, sol-gel method, deposition of synthesized SnO<sub>2</sub> nanoparticles (NPs), and commercialized SnO<sub>2</sub> colloidal precursors.<sup>92–94</sup> In the meantime, spin-coating,<sup>95–98</sup> spray-coating,<sup>99–101</sup> slot-die coating,<sup>100,102,103</sup> roll-to-roll microgravity printing,<sup>104</sup> blade-coating<sup>105,106</sup> and inkjet-printing<sup>107,108</sup> are valuable technologies to fabricate quality SnO<sub>2</sub> films.

**2.1.1 Thermal decomposition method.** For thermal decompositions, Sn-based salts (SnCl<sub>2</sub>,<sup>109,110</sup> or SnCl<sub>4</sub>,<sup>111–113</sup> or their hydrates SnCl<sub>2</sub>·2H<sub>2</sub>O<sup>114,115</sup> or SnCl<sub>4</sub>·5H<sub>2</sub>O<sup>116,117</sup>) were first dissolved in polar solvents such as alcohol and deionized water, which were then deposited on an ITO or a FTO substrate by spin-coating and gradually converted into SnO<sub>2</sub> through thermal annealing in ambient air. It should be noticed that the humidity and temperature of the environment significantly influence the annealing process and the quality of the obtained SnO<sub>2</sub> films.

Zhang and co-workers prepared SnO<sub>2</sub> thin films using SnCl<sub>4</sub> as the tin source at low temperatures.<sup>112</sup> Furthermore, they compared the passivation by SnCl<sub>4</sub> at FTO/ETL with that at the ETL/perovskite interface to study the effect of the SnCl<sub>4</sub> pre-treatment and post-treatment on SnO<sub>2</sub> (Fig. 4a). With the assistance of SnCl<sub>4</sub> pre-treatment, the devices based on Cl-SnO<sub>2</sub>

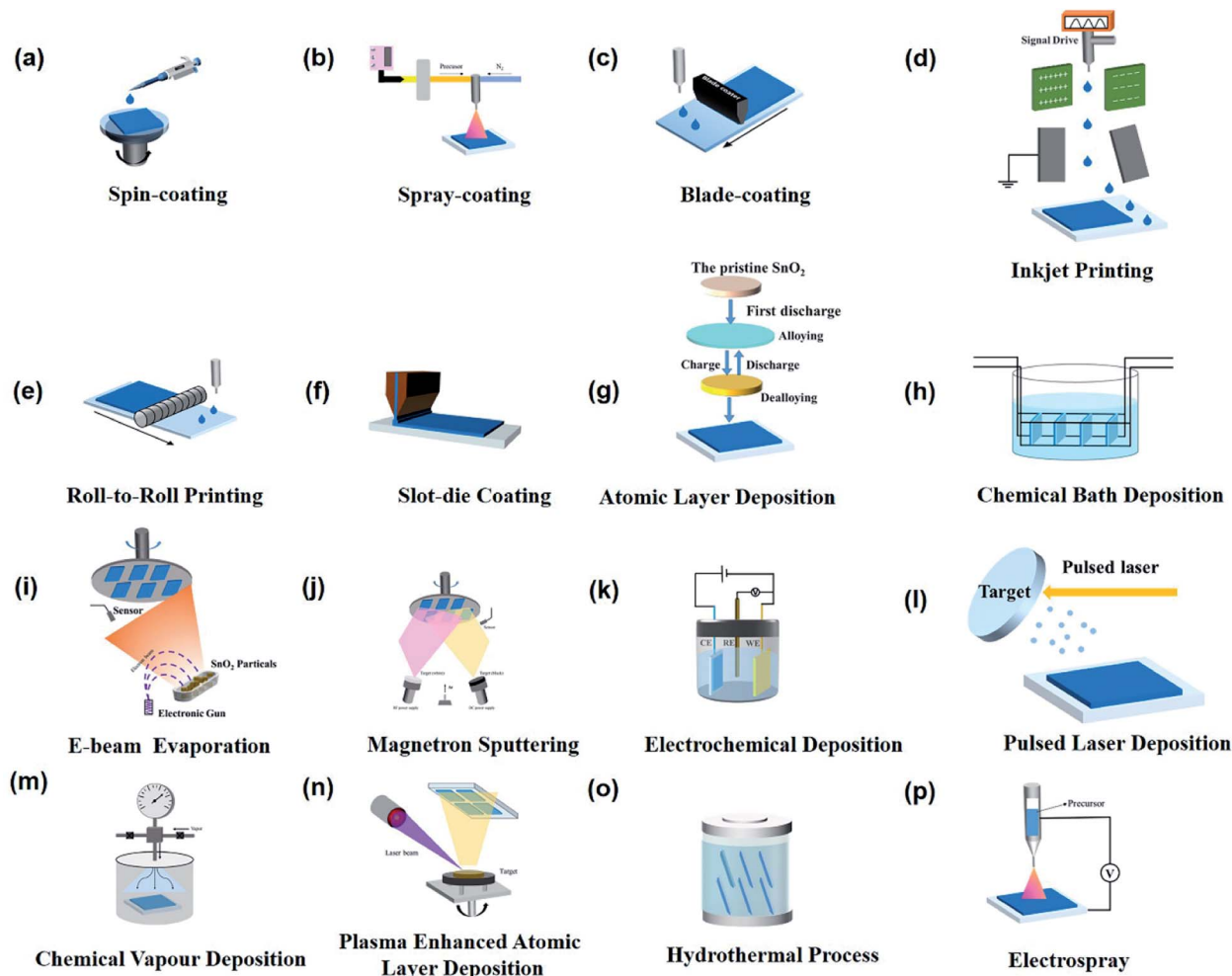


Fig. 3 Schematic illustration of common  $\text{SnO}_2$  deposition processes in PSCs. (a) Spin-coating. (b) Spray-coating. (c) Blade-coating. (d) Inkjet-printing. (e) Roll-to-roll printing. (f) Slot-die coating. (g) Atomic layer deposition. (h) Chemical bath deposition. (i) E-beam evaporation electro-spray. (j) Magnetron sputtering. (k) Electrochemical deposition. (l) Pulsed laser deposition. (m) Chemical vapor deposition. (n) Plasma enhanced atomic layer deposition. (o) Hydrothermal process. (p) Electro spray.

ETL obtained the best efficiency of 18.6% as compared to the post-treatment process (17.3%). The results confirmed that both modifications could boost the photovoltaic performance of the PSCs. However,  $\text{SnCl}_4$  pre-treatment increased  $\text{SnO}_2$  ETL in electron coupling with FTO, leading to higher electron mobility and better charge extraction efficiency.<sup>112</sup>

Annemarie Pucci and co-workers prepared  $\text{SnO}_2$  thin films using  $\text{SnCl}_2 \cdot 2\text{H}_2\text{O}$  as the tin source. Their work elucidated the influence of two different solvents and various annealing temperatures on the layer morphology of  $\text{SnO}_2$  thin films. It was found that different morphologies were mainly observed during the spin-coating process and not the subsequent annealing process. Furthermore, high annealing temperatures ( $\approx 400^\circ\text{C}$ ) do not entirely omit the differences in morphology, which were processed from the two kinds of solution systems. Although this device still showed severe hysteresis, the device with inkjet-printed  $\text{SnO}_2$  layers presented the highest output efficiency of about 19%.<sup>107</sup>

**2.1.2 Sol-gel method.** Sol-gel is one of the most commonly used methods to produce thin dense films and powder catalysts

at large homogeneous concentrations and under stoichiometry control because of the simplicity, low energy, reliability, reproducibility, and relatively mild fabrication conditions.<sup>118–121</sup>

Lee and co-workers introduced a simple sol-gel method to form a  $\text{SnO}_2$  bilayer ( $\text{Bi-SnO}_2$ ) as ETL with dopant-free and amorphous-crystalline heterophase properties by a sequential spin-coating process.  $\text{Bi-SnO}_2$  demonstrated a smooth morphology, low density of energy level traps, and appropriate bandgap matching. As a consequence,  $\text{Bi-SnO}_2$  PSCs with active areas ( $\approx 3.55\text{ cm}^2$ ) reached up to about 15% with less hysteresis.<sup>122</sup> Xu *et al.* optimized the aging time, and the PSCs based on the sol-gel  $\text{SnO}_2$  film yielded the best PCE of 19% with excellent light trapping ability and a textured  $\text{SnO}_2$  structure. But the sol-gel  $\text{SnO}_2$  film suffered from poor interfacial contact electrical properties with the perovskite absorber layer because of the annealing effects, resulting in the degradation of performance of PSCs.<sup>123</sup>

Wang *et al.* reported a whole sol-gel crystallized  $\text{SnO}_2$  fabrication process below  $80^\circ\text{C}$  (Fig. 4b).<sup>114</sup> Participation of environmental  $\text{O}_2$  and  $\text{H}_2\text{O}$  via various methods of refluxing is

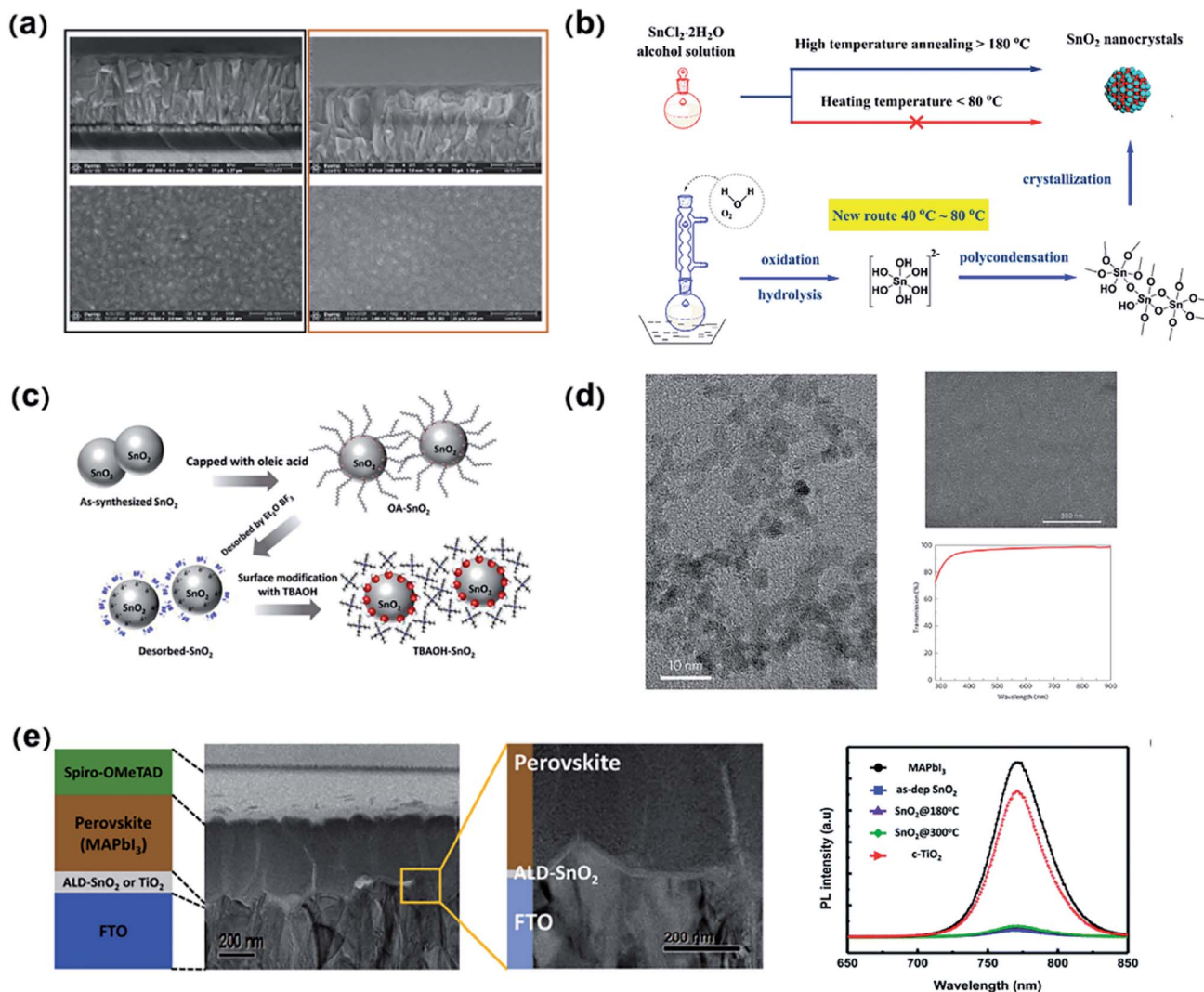


Fig. 4 (a) Cross-sectional and top-view SEM images (left) of the FTO/SnO<sub>2</sub> NC substrate and (right) FTO/Cl-SnO<sub>2</sub>. Reproduced with permission.<sup>112</sup> Copyright 2020, Elsevier. (b) Schematic diagram of the wet chemical route to synthesize SnO<sub>2</sub> nanocrystals. Reproduced with permission.<sup>114</sup> Copyright 2017, Elsevier. (c) Schematic illustration of the ligand exchange procedure for TBAOH-capped SnO<sub>2</sub> nanoparticles. Reproduced with permission.<sup>124</sup> Copyright 2017, ACS Publishing Group. (d) TEM and SEM images of SnO<sub>2</sub> nanoparticles and the transmission spectrum of SnO<sub>2</sub> films. Reproduced with permission.<sup>44</sup> Copyright 2017, Nature Publishing Group. (e) Device architecture and cross-sectional TEM images, and PL spectra of the device based on the ALD-SnO<sub>2</sub> films. Reproduced with permission.<sup>125</sup> Copyright 2019, Royal Society of Chemistry.

essential as it could substantially lower the Sn<sup>2+</sup> oxidation and lead to the hydrolysis of SnCl<sub>2</sub>·2H<sub>2</sub>O alcohol solution, alternatively establishing an energetically favorable pathway for SnO<sub>2</sub> crystallization at low temperatures. The devices had a PCE and a steady-state PCE of 19.20% and 18.48%, respectively, which are significantly better than those of the devices based on high temperature annealed TiO<sub>2</sub> ETLs (16.61% and 15.03%).

**2.1.3 SnO<sub>2</sub> nanoparticle synthesis method.** It is an efficient method to prepare a compact SnO<sub>2</sub> film by depositing synthesized SnO<sub>2</sub> nanoparticles (NPs) for high performance PSCs.<sup>126,127</sup> To reduce the recombination centers in the SnO<sub>2</sub> film, SnO<sub>2</sub> NPs should be washed prior to the removal of residuals after synthesizing SnO<sub>2</sub>. The main issues for the utilization of SnO<sub>2</sub> NPs are the dispersibility and the choice of solvent. A suitable

solvent should be able to disperse NPs nicely and should not damage the perovskite layer.

Lee and co-workers selected tetrabutylammonium hydroxide (TBAOH) to successfully disperse SnO<sub>2</sub> NPs (TBAOH-SnO<sub>2</sub>) well in ethanol *via* the ligand exchange method (Fig. 4c).<sup>124</sup> Using this TBAOH-SnO<sub>2</sub> NPs as ETL, the PSCs effectively reached up to 18.77% because of minor charge accumulation and good energy level alignment. Besides, the device with a TBAOH-SnO<sub>2</sub> NPs layer only reduced approximately 10% in PCE, which showed improved thermal stability by TBAOH treatment.<sup>124</sup> For SnO<sub>2</sub> deposition, the crystallinity and morphology of the SnO<sub>2</sub> films significantly relied on the annealing temperature.

Park and co-workers investigated the SnO<sub>2</sub> formation at different annealing temperatures (RT, 80 °C, 120 °C, 160 °C, and

200 °C). It was found that when SnO<sub>2</sub> was annealed at 120 °C, the champion PCE was obtained (19.0%). Using AFM and UPS, both the smooth surface and suitable band alignment of SnO<sub>2</sub> film deposition at low temperatures have been observed, contributing to obtaining a high PCE and long stability of the device.<sup>73</sup> However, traditional deposition of the SnO<sub>2</sub> film imposes restrictions on the substrate choice and commercial applications because of a relatively high temperature and/or a long-duration sintering step. Many scientists came up with other creative post-annealing processes to deal with this problem, including microwave-assisted annealing,<sup>126</sup> intense pulsed photonic annealing,<sup>128</sup> and UV-sintering methods.<sup>129,130</sup>

**2.1.4 SnO<sub>2</sub> colloidal precursor.** You *et al.* formed a compact and uniform SnO<sub>2</sub> film by using a commercialized SnO<sub>2</sub> colloidal precursor (Fig. 4d).<sup>44</sup> The process was that the SnO<sub>2</sub> colloidal nanoparticle precursor was spin-coated at the medium speed rate on top of the ITO electrode. These substrates were annealed at 150 °C for 30 min to evaporate water. The device with SnO<sub>2</sub> film deposition at low temperatures initially achieved 19.9% certified efficiency. Later on, introducing a surface passivation layer of PbI<sub>2</sub> and an organic halide salt phenethylammonium iodide (PEAI) boosted the certified efficiency to 20.9%<sup>131</sup> and 23.32%.<sup>35</sup> Tan and co-worker added KCl to the SnO<sub>2</sub> colloidal precursor to passivate the ETL/perovskite interface and at the grain boundaries by K/Cl ions (SnO<sub>2</sub>-KCl).<sup>132</sup> The strategy can enhance the *V*<sub>oc</sub> from 1.077 to 1.137 V, and a corresponding PCE increased from 20.2% to 22.2% for the devices using SnO<sub>2</sub>-KCl composite ETL.

## 2.2 Atomic layer deposition (ALD)

ALD is considered a promising deposition technique to fabricate ultra-thin and dense metal oxide layers with increased light transmittance based on a self-limiting surface reaction. Due to the precise control at the atomic level, the high-quality film of metal oxides has the merits of promoting charge transfer, suppressing the degradation caused by the external environment and internal ionic migration, and enhancing the photoelectric properties of the device.<sup>133,134</sup>

Lee and co-workers prepared planar SnO<sub>2</sub>-based PSCs using ALD by modulating the deposition and post-annealing temperatures. It was found that the post-annealing process can effectively passivate the perovskite and SnO<sub>2</sub> interface, leading to reduced charge recombination. As a result, SnO<sub>2</sub> based PSC with post-annealing achieved a PCE of 20% with high reproducibility and stability.<sup>135</sup> Grätzel and co-workers prepared an amorphous SnO<sub>2</sub> film by ALD, which can maintain its dense morphological characteristics even during the annealing process at 450 °C.<sup>87</sup>

Jeong and co-workers deposited thin SnO<sub>2</sub> films by ALD with subsequent annealing at 180 °C as ETLs. In the cross-sectional image by transmission electron microscopy (TEM), the thicknesses of the SnO<sub>2</sub> film were around 12 nm, similar to those of TiO<sub>2</sub> (Fig. 4e). Compared with the c-TiO<sub>2</sub>/MAPbI<sub>3</sub> sample, SnO<sub>2</sub>@180 °C/MAPbI<sub>3</sub> showed a much decrease in PL intensity (≈ 94%), which exhibited an increase in photo-generated electron extraction from perovskite. Finally, PSCs based on SnO<sub>2</sub>

with annealing at 180 °C showed the highest PCE (>18%) with better reproducibility.<sup>125</sup> Although ALD has these attractive advantages, it is necessary to deposit thin films under vacuum conditions and a matched operating space for scalable fabrication, resulting in high preparation costs.

## 2.3 Chemical bath deposition (CBD)

CBD is seen as a valuable technique to deposit a thin film of metal oxides as a buffer layer in photovoltaic cells, which has many advantages such as low fabrication cost, low-temperature process, suitability for different electrodes, and great reproducibility.<sup>136-138</sup>

Jun Hong Noh and co-workers prepared SnO<sub>2</sub> by CBD as ETL and employed poly(3-hexylthiophene) (P3HT) with gallium(III) acetylacetonate (Ga(acac)<sub>3</sub>) additives. Consequently, they boosted the performance of free-doping PCE over 24% with a *V*<sub>oc</sub> of 1.15 V and a FF of 83.8%. It also showed superior water-resistant property for 2000 h under 85% RH without any encapsulation.<sup>139</sup> Ko and co-workers fabricated a self-controlled SnO<sub>2</sub> through a convenient CBD.<sup>140</sup> It was found that the common-ion and precursor concentrations can effectively tune the growth of the SnO<sub>2</sub> film on FTO, leading to a uniform and compact SnO<sub>2</sub> layer. Finally, the device with a hydrolyzed SnO<sub>2</sub> layer presented an excellent PCE of 20.21%.

Yoo and co-workers first prepared SnO<sub>2</sub> as the ETL using CBD by controlling the formation of Sn intermediate species, which depended on the decomposition pathway of the Sn<sup>2+</sup> precursor (SnCl<sub>2</sub>), including four stages. Their SEM images of the SnO<sub>2</sub> layer showed that as the reaction time increases, the pH of the reaction solution increased, and the size of the SnO<sub>2</sub> domain increased from around 50 nm to about 100 nm. Especially, a SnO<sub>2</sub> layer formed a complete coverage on FTO at stage A-ii (pH 1.5), which can be observed from TEM images. The XRD confirmed the presence of various Sn intermediate species, which relied on the pH of the reaction solution (Fig. 5). Moreover, they added the MAPbBr<sub>3</sub> + MACl additive in perovskite to stabilize the intermediate phase, enhance the perovskite orientation, and introduce alkylammonium bromide for the 2D perovskite passivation. Due to the holistic method, they obtained a certified PCE of 25.2% (Table 1).<sup>36</sup> Despite the merits of simple operation and low cost, the quality of films in CBD is strongly determined by the processing parameters, including the temperature, concentration, and pH. In the meantime, the pollution of residual precursors after fabrication and the necessity for frequent bath replacement are also critical issues for the commercialization of PSCs.

## 2.4 E-beam evaporation

E-beam evaporation is one of the high vacuum techniques, which generates more compact films and minimal waste of resources in contrast to the spin-coating process and ALD, and is beneficial to the large-scale application and commercialization of PSCs.<sup>141</sup>

Ma and co-worker fabricated SnO<sub>2</sub> as ETL by e-beam evaporation for possible commercialization of PSCs with large-scale manufacture. As the SnO<sub>2</sub> target source evaporated, the e-beam

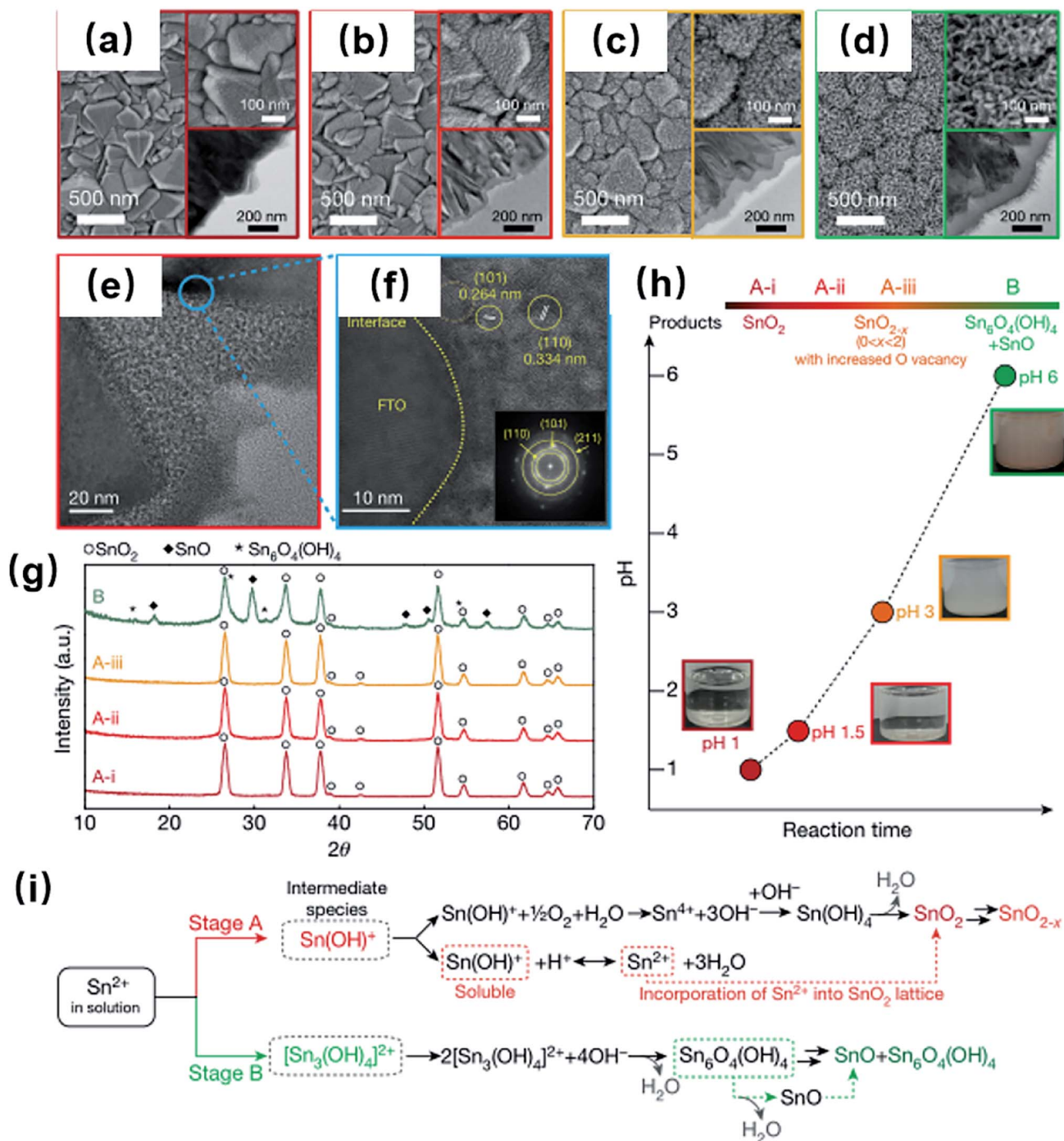


Fig. 5 (a–d) SEM images of SnO<sub>2</sub> at different stages: (a) A-i; (b) A-ii; (c) A-iii; and (d) B. The insets shown are SEM (top-right) and the corresponding cross-sectional TEMs (bottom-right). (e) and (f) High-resolution TEM images of SnO<sub>2</sub> at stage A-ii (the inset: a fast Fourier transform pattern of the TEM image). (g) XRD patterns of the SnO<sub>2</sub> films at different reaction stages. (h) Schematic illustration of the reaction progress with a photograph of the reaction solution at each stage. (i) Schematic illustration of the overall reaction mechanism for forming the SnO<sub>2</sub>-based films. Reproduced with permission.<sup>36</sup> Copyright 2021, Nature Publishing Group.

evaporation process could simulate thousands of SnO<sub>2</sub> film substrates at one time by changing the position of the substrate holder. The advantages of e-beam evaporation were that the thickness and the crystallinity of the SnO<sub>2</sub> film could be controlled precisely. Consequently, the PSCs with a uniform SnO<sub>2</sub> film by e-beam evaporation demonstrated excellent performance of 18.2%

and remarkable waterproof, which retained 97% of its original efficiency value with a relative humidity of 85% for over 34 days.<sup>142</sup> Despite the relatively high deposition rates, e-beam evaporation has the disadvantage of controlling the film composition precisely.

Later, to reduce the resistivity of SnO<sub>2</sub>, Song and co-workers prepared SnO<sub>2</sub> ETL by e-beam evaporation combined with Zn

Table 1 Representative PSCs based on SnO<sub>2</sub> ETL fabricated by different preparation methods<sup>a</sup>

| Device structure   | Perovskite   | Deposition method                    | Tin source                                       | $J_{sc}$ (mA cm <sup>-2</sup> ) | $V_{oc}$ (V) | FF (%) | PCE (%) | Ref. |
|--|--|--------------------------------------|--|---------------------------------|--------------|--------|---------|------|
| ITO/SnO <sub>2</sub> /PCBM:Bphen/perovskite/HTL(a)/Au            | Cs <sub>0.04</sub> FA <sub>0.92</sub> MA <sub>0.04</sub> PbI <sub>3</sub>  | Spin-coating                         | SnO <sub>2</sub> colloidal precursor             | 25.15                           | 1.167        | 78.64  | 20.39   | 122  |
| ITO/SnO <sub>2</sub> /perovskite/HTL(a)/Au                       | MAPbI <sub>3</sub>   | Spin-coating                         | SnCl <sub>4</sub>                                | 23.2                            | 1.12         | 71.4   | 18.6    | 112  |
| FTO/SnO <sub>2</sub> /perovskite/HTL(a)/Au                       | MAPbI <sub>3</sub>   | Spin-coating                         | SnCl <sub>2</sub> ·2H <sub>2</sub> O             | 22.88                           | 1.06         | 82.54  | 18.89   | 123  |
| ITO/SnO <sub>2</sub> /perovskite/HTL(a)/Au                       | Cs <sub>0.05</sub> FA <sub>0.79</sub> MA <sub>0.16</sub> PbI <sub>2.45</sub> Br <sub>0.55</sub>                                    | Spray-coating                        | SnO <sub>2</sub> colloid dispersion              | 22.2                            | 1.17         | 76.1   | 19.8    | 100  |
| FTO/SnO <sub>2</sub> :GQDs/perovskite/HTL(a)/Au                  | (FAPbI <sub>3</sub> ) <sub>0.85</sub> (MAPbBr <sub>3</sub> ) <sub>0.15</sub>   | Spray-coating                        | SnCl <sub>2</sub> ·2H <sub>2</sub> O             | 22.5                            | 1.12         | 65.8   | 17.08   | 99   |
| FTO/SnO <sub>2</sub> /perovskite/HTL(a)/Au                       | MAPbI <sub>3</sub>   | Spray-coating                        | SnO <sub>2</sub> colloid dispersion              | 21.63                           | 1.002        | 78     | 16.91   | 101  |
| ITO/SnO <sub>2</sub> /perovskite/HTL(a)/Au                       | Cs <sub>0.05</sub> (FA <sub>0.85</sub> MA <sub>0.15</sub> ) <sub>0.95</sub> Pb(I <sub>0.85</sub> Br <sub>0.15</sub> ) <sub>3</sub> | Slot-die-coating                     | SnO <sub>2</sub> colloid dispersion              | 22.60                           | 1.148        | 79     | 20.50   | 103  |
| PEN/ITO/SnO <sub>2</sub> /perovskite/HTL(a)/Ag                   | FA <sub>x</sub> MA <sub>y</sub> Cs <sub>1-x-y</sub> Pb(I <sub>z</sub> Br <sub>1-z</sub> ) <sub>3</sub>                             | Roll-to-roll                         | SnO <sub>2</sub> colloid dispersion              | 19.96                           | 1.07         | 70.09  | 16.60   | 104  |
| ITO/SnO <sub>2</sub> /perovskite/HTL(a)/Ag                       | Cs/FA <sub>x</sub> MA <sub>1-x</sub> PbI <sub>y</sub> Br <sub>3-y</sub>  | Blade-coating                        | SnO <sub>2</sub> colloid dispersion              | 23.1                            | 1.08         | 72     | 18      | 106  |
| FTO/SnO <sub>2</sub> /perovskite/HTL(a)/Au                       | CsPbI <sub>3</sub>   | Blade-coating                        | SnO <sub>2</sub> colloid dispersion              | 20.67                           | 1.12         | 81.98  | 19      | 105  |
| ITO/SnO <sub>2</sub> /perovskite/HTL(a)/Au                       | Cs <sub>0.10</sub> FA <sub>0.75</sub> MA <sub>0.15</sub> Pb(Br <sub>0.15</sub> I <sub>0.85</sub> ) <sub>3</sub>                    | Inkjet-printing                      | SnCl <sub>2</sub> ·2H <sub>2</sub> O             | 23.6                            | 1.11         | 72     | 18.8    | 107  |
| FTO/SnO <sub>2</sub> /perovskite/HTL(a)/Au                       | MAPbI <sub>3</sub>   | ALD                                  | C <sub>8</sub> H <sub>24</sub> N <sub>4</sub> Sn | 22.6                            | 1.07         | 75.6   | 18.3    | 125  |
| FTO/SnO <sub>2</sub> /TiO <sub>2</sub> /perovskite/HTL(a)/Au     | (FAPbI <sub>3</sub> ) <sub>0.85</sub> (MAPbBr <sub>3</sub> ) <sub>0.15</sub>   | ALD                                  | C <sub>8</sub> H <sub>24</sub> N <sub>4</sub> Sn | 22.67                           | 1.13         | 78     | 20.03   | 135  |
| FTO/SnO <sub>2</sub> /perovskite/HTL(a)/Au                       | FAPbI <sub>3</sub>   | CBD                                  | SnCl <sub>2</sub> ·2H <sub>2</sub> O             | 25.09                           | 1.194        | 84.7   | 25.4    | 36   |
| FTO/SnO <sub>2</sub> /perovskite/HTL(b)/Au                       | (FAPbI <sub>3</sub> ) <sub>0.95</sub> (MAPbBr <sub>3</sub> ) <sub>0.05</sub>   | CBD                                  | SnCl <sub>2</sub> ·2H <sub>2</sub> O             | 25.5                            | 1.15         | 83.8   | 24.6    | 139  |
| FTO/SnO <sub>2</sub> /perovskite/HTL(a)/Au                       | Cs <sub>0.05</sub> (MA <sub>0.17</sub> FA <sub>0.83</sub> ) <sub>0.95</sub> Pb(I <sub>0.83</sub> Br <sub>0.17</sub> ) <sub>3</sub> | E-beam evaporation                   | SnO <sub>2</sub> powders                         | 22.47                           | 1.08         | 71     | 17.38   | 142  |
| FTO/Zn-SnO <sub>2</sub> /perovskite/HTL(a)/Au                    | FA <sub>x</sub> MA <sub>y</sub> Cs <sub>1-x-y</sub> Pb(I <sub>z</sub> Br <sub>1-z</sub> ) <sub>3</sub>                             | E-beam evaporation                   | SnO <sub>2</sub> powders                         | 22.72                           | 1.11         | 75     | 18.95   | 143  |
| FTO/SnO <sub>2</sub> /perovskite/HTL(a)/Au                       | Cs <sub>0.06</sub> MA <sub>0.27</sub> FA <sub>0.67</sub> PbI <sub>2.7</sub> Br <sub>0.3</sub>                                      | Magnetron sputtering                 | SnO <sub>2</sub> target                          | 23.7                            | 1.08         | 79     | 20.2    | 148  |
| FTO/SnO <sub>2</sub> /perovskite/HTL(a)/Au                       | FA <sub>0.85</sub> MA <sub>0.15</sub> Pb(I <sub>0.85</sub> Br <sub>0.15</sub> ) <sub>3</sub>                                       | Magnetron sputtering                 | SnO <sub>2</sub> target                          | 22.58                           | 1.065        | 75.6   | 18.2    | 149  |
| FTO/SnO <sub>2</sub> /PCBM/perovskite/HTL(a)/Au                  | MAPbI <sub>3</sub>   | PLD                                  | SnO <sub>2</sub> target                          | 21.51                           | 1.11         | 73     | 17.29   | 164  |
| FTO/SnO <sub>2</sub> /C <sub>60</sub> -SAM/perovskite/HTL(a)/Au  | MA <sub>0.7</sub> FA <sub>0.3</sub> PbI <sub>3</sub>   | PEALD                                | SnO <sub>2</sub> target                          | 22.71                           | 1.113        | 80.75  | 20.41   | 156  |
| ITO/SnO <sub>2</sub> /PCBM/perovskite/HTL(a)/Ag                  | MAPbI <sub>3</sub>   | Electrodeposition                    | SnCl <sub>2</sub>                                | 19.75                           | 1.08         | 65     | 13.88   | 150  |
| FTO/SnO <sub>2</sub> /perovskite/HTL(a)/Au                       | Cs <sub>0.05</sub> (MA <sub>0.17</sub> FA <sub>0.83</sub> ) <sub>0.95</sub> Pb(I <sub>0.83</sub> Br <sub>0.17</sub> ) <sub>3</sub> | Combustion                           | SnCl <sub>2</sub> ·2H <sub>2</sub> O             | 23.85                           | 1.122        | 78.2   | 20.92   | 165  |
| FTO/SnO <sub>2</sub> /PCBM/perovskite/HTL(a)/Ag                  | MAPbI <sub>3</sub>   | CVD                                  | SnCl <sub>2</sub>                                | 14.7                            | 1.03         | 67.51  | 10.2    | 159  |
| FTO/SnO <sub>2</sub> /C60/perovskite/HTL(a)/Au                   | MAPbI <sub>3</sub>   | Electrospray                         | SnCl <sub>2</sub> ·2H <sub>2</sub> O             | 23.7                            | 1.103        | 77.3   | 20.2    | 163  |
| FTO/SnO <sub>2</sub> /perovskite/HTL(a)/Au                       | Cs <sub>0.05</sub> (MA <sub>0.17</sub> FA <sub>0.83</sub> ) <sub>0.95</sub> Pb(I <sub>0.83</sub> Br <sub>0.17</sub> ) <sub>3</sub> | Hydrothermal                         | SnCl <sub>4</sub> ·5H <sub>2</sub> O             | 22.69                           | 1.129        | 72.70  | 18.62   | 117  |
| FTO/SnO <sub>2</sub> /perovskite/HTL(a)/Au                       | MAPbI <sub>3</sub>   | Thermal evaporation                  | SnO <sub>2</sub> powder                          | 23.36                           | 1.04         | 69.2   | 16.79   | 161  |
| P-FTO/perovskite/HTL(a)/Au                                       | MAPbI <sub>3</sub>   | <i>In situ</i> plasma etching of FTO | Commercial FTO substrate                         | 23.85                           | 1.11         | 77.12  | 20.39   | 160  |
| FTO/G-SnO <sub>2</sub> /C-SnO <sub>2</sub> /perovskite/HTL(a)/Au | Cs <sub>0.05</sub> (MA <sub>0.17</sub> FA <sub>0.83</sub> ) <sub>0.95</sub> Pb(I <sub>0.83</sub> Br <sub>0.17</sub> ) <sub>3</sub> | Ball-milling                         | SnO <sub>2</sub> powder                          | 21.16                           | 1.22         | 80.09  | 21.09   | 158  |

<sup>a</sup> HTL(a): spiro-OMeTAD; HTL(b): poly(3-hexylthiophene) (P3HT); C<sub>8</sub>H<sub>24</sub>N<sub>4</sub>Sn: tetrakis(dimethylamido)tin(IV); GQDs: graphene quantum dots; CBD: chemical bath deposition; PLD: pulse laser deposition; ALD: atomic layer deposition; CVD: chemical vapor deposition; PEALD: plasma-enhanced atomic-layer deposition.

doping (Zn-SnO<sub>2</sub>). Following Zn doping, the Zn-SnO<sub>2</sub> layer improved the charge mobility, inhibited the charge accumulation at the interface, and optimized the SnO<sub>2</sub> energy level structure, resulting in a PCE increase from 18.95% to 20.16% with long-term stability. More importantly, after 100 bending tests, the flexible device maintained a PCE of over 15% (Fig. 6a and b).<sup>143</sup> Furthermore, Li and co-workers used an oxygen

plasma-triggered e-beam evaporation approach to create SnO<sub>2</sub> films at ambient temperature without annealing. The oxygen plasma can precisely tune the stoichiometry of SnO<sub>2</sub> films in the evaporation process due to its intense oxidation activity, thereby endowing SnO<sub>2</sub> with uniformity, high transmittance, high Hall mobility, and good hydrophilicity.<sup>144</sup> Aside from the requirement



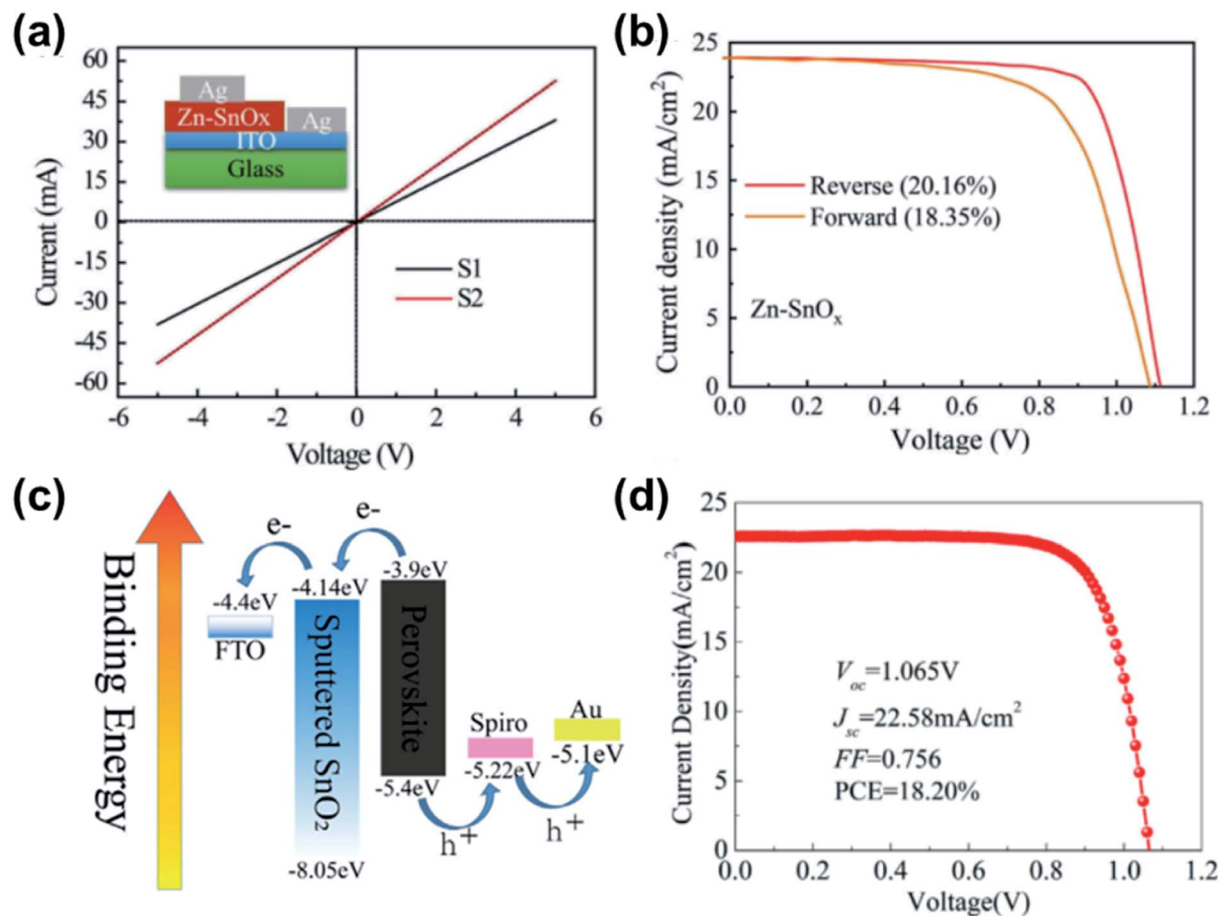


Fig. 6 (a) Conductivity of bare  $\text{SnO}_x$  (S1) and  $\text{Zn-SnO}_x$  (S2); (b) the reverse scan  $J$ - $V$  curves of the device based on  $\text{Zn-SiO}_x$ . Reproduced with permission.<sup>145</sup> Copyright 2020, Wiley-VCH. (c) Energy level scheme for various layers in a sputtered  $\text{SnO}_2$  based device. (d)  $J$ - $V$  curves under the reverse voltage scan of the best device with sputtered  $\text{SnO}_2$ . Reproduced with permission.<sup>149</sup> Copyright 2019, Elsevier.

for a high vacuum, this approach is limited by X-ray damage on substrates and slow conduction speeds.

## 2.5 Magnetron sputtering

Magnetron sputtering is a mature and reliable deposition method with the use of low-cost metal-oxide targets to prepare metal-oxide thin films in the lab- and industrial-scale.<sup>145,146</sup>  $\text{SnO}_2$  particles are sputtered by high energy argon ions, react with the reaction gas (like high purity oxygen), and then deposited on the top of the FTO, which is a continuous process. Magnetron sputtering has excellent merits, including the precise control of film density and thickness, low waste of raw materials, a mild deposition process, and low production cost. Besides, the deposition process is usually operated in a high vacuum chamber, leading to high repeatability with minor damage to the natural environment.<sup>147</sup>

Qiu and co-workers systematically investigated the chemical and physical characteristics of sputtered  $\text{SnO}_2$ . It played a significant role in the formation of high quality to control the oxidizing process. Through improvement in the device architecture, the device with sputtered  $\text{SnO}_2$  ETL exhibited the champion PCE of 20.2% and a useful life of 625 h under  $T_{30}$  measurement,

confirming the enhanced conductivity of  $\text{SnO}_2$ .<sup>148</sup> Meanwhile, Bai and co-workers discovered that while changing the working gas ratio of  $\text{Ar}/\text{O}_2$  can result in identical shape and crystallinity of sputtered  $\text{SnO}_2$ , it can also result in different trap states and carrier transit dynamics in PSC devices. The devices based on sputtered  $\text{SnO}_2$  ETL demonstrated a champion PCE (up to 18.20%) (Fig. 6c and d).<sup>149</sup> Additionally, Otoufi and co-workers introduced sputtered  $\text{SnO}_2$  on the  $\text{TiO}_2$  layer to form  $\text{TiO}_2/\text{SnO}_2$  bilayers to improve electron extraction further and achieve a better PCE of 12.3% in comparison with only  $\text{TiO}_2$  as ETL (8.18%).<sup>146</sup> The gas flows played a crucial role in controlling the oxygen vacancies. On the other hand, tail states within the bandgap are caused by the amorphous or nanocrystallinity in the films, which are effectively suppressed by interface passivation.

## 2.6 Other deposition methods

Besides the solution-processable and vacuum evaporation methods, other creative methods are emerging for high-quality  $\text{SnO}_2$  films due to demands for different applications. For example, Chen *et al.* prepared PSCs with  $\text{SnO}_2$ -ETLs by electrochemical deposition. The PSCs using  $\text{MAPbI}_3$  as the light-absorbing layer obtained a PCE of 13.88% with negligible

hysteresis.<sup>150</sup> The electrochemical deposition was beneficial for SnO<sub>2</sub> preparation at low temperatures (50 °C) without introducing a seed layer or a post-treatment process.<sup>151</sup> The dual-fuel combustion method was usually an excellent choice to control the SnO<sub>2</sub> growth.<sup>152,153</sup> Compared to the conventional solution-process method, as combustion synthesis was ignited, the method not only requires significant external energy input but also is exothermic, leading to reduced production cost.

Additionally, other physical and chemical preparation technologies were also used to deposit SnO<sub>2</sub> ETLs, including plasma-enhanced atomic layer deposition (PEALD),<sup>154–157</sup> high energy ball-milling,<sup>158</sup> chemical vapor deposition (CVD),<sup>159</sup> *in situ* plasma etching of FTO,<sup>160</sup> thermal evaporation,<sup>161</sup> hydrothermal processes,<sup>117,162</sup> and electro spray method.<sup>163</sup> In these methods, the SnO<sub>2</sub> film crystallized well during the deposition process on the substrates without further post-heating treatment. Thus, these methods demonstrate significant advantages for the mass production of flexible PSCs, even though the process tends to take much time.

### 3. Nanostructures of SnO<sub>2</sub>

3D SnO<sub>2</sub> materials such as SnO<sub>2</sub> nanoparticles or nanocrystals are commonly exploited as ETL.<sup>83</sup> However, Zhao *et al.* found that 0D–2D SnO<sub>2</sub> ETLs can reduce light scattering from rough FTO and enlarge the perovskite grain size, leading to improved performance.<sup>166</sup> Nanostructured SnO<sub>2</sub> is a critical factor for high-efficiency PSCs to scale up planar PSCs for industrial applications. On the one hand, it can optimize the surface wettability for smooth perovskite coverage on the substrate. On the other hand, nanostructured SnO<sub>2</sub> (Fig. 7) enhances the interfacial contact to eliminate the notorious electronic trap states, which removes the energy level traps at the interface. So, the dimensional control of SnO<sub>2</sub> is a promising strategy to prepare SnO<sub>2</sub> ETL with a high photoelectrical property.

#### 3.1 SnO<sub>2</sub> nanowires

SnO<sub>2</sub> nanowires (NWs), a one-dimensional (1D) semiconductor material, are a good ETL in the field of PSCs due to their

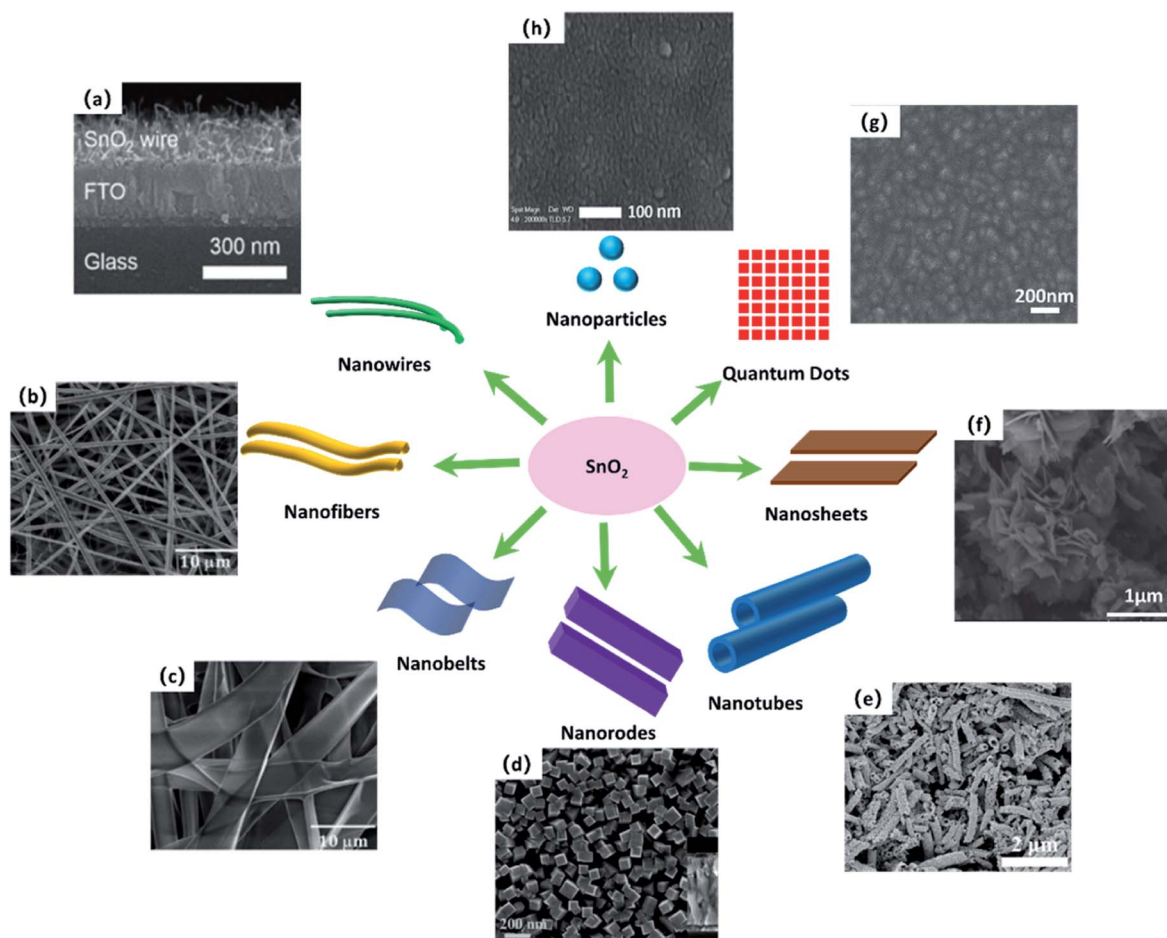


Fig. 7 Schematic diagram of various nanostructures of SnO<sub>2</sub> in accordance with SEM images of various SnO<sub>2</sub> nanostructures: (a) nanowires reproduced with permission.<sup>167</sup> Copyright 2015, Royal Society of Chemistry. (b) Nanofibers and (c) nanobelts. Reproduced with permission.<sup>168</sup> Copyright 2018, Royal Society of Chemistry. (d) Nanorods. Reproduced with permission.<sup>169</sup> Copyright 2018, Wiley-VCH. (e) Nanotubes. Reproduced with permission.<sup>170</sup> Copyright 2020, Elsevier. (f) Nanosheets. Reproduced with permission.<sup>171</sup> Copyright 2016, Elsevier. (g) Quantum dots. Reproduced with permission.<sup>95</sup> Copyright 2018, Wiley-VCH; (h) nanoparticles. Reproduced with permission,<sup>83</sup> Copyright 2015, ACS Publishing Group.

efficient extraction and collection capacity. Besides, 1D nano-materials have fewer defects like grain boundaries which significantly decrease in dead-ends.<sup>172–176</sup>

Han and co-workers synthesized 1D SnO<sub>2</sub> as the ETL by a vapor–liquid–solid (VLS) reaction for realizing high conductivity for SnO<sub>2</sub> (Fig. 7a). The SnO<sub>2</sub> NWs showed a high transmittance of about 80%, similar to that of the bare FTO substrate, as observed from the UV-vis transmittance spectrum. SnO<sub>2</sub> NWs were modified with TiO<sub>2</sub> nanoshells as TiO<sub>2</sub>/SnO<sub>2</sub> NW ETL *via* plasma-enhanced atomic layer deposition (PEALD). Consequently, the TiO<sub>2</sub>/SnO<sub>2</sub> NW ETL device displayed over 95% absorbed photon-to-current conversion efficiency (APCE) at 750 nm with a PCE of 14.2% and decreased the electron transport time by one order of magnitude in comparison with that of mp-ETL-based devices.<sup>167</sup>

### 3.2 SnO<sub>2</sub> nanofibers and nanobelts

1D SnO<sub>2</sub> nanofibers (NFs) and nanobelts (NBs) demonstrate fast electron transport rate and light scattering ability used in the dye-sensitized solar cells (DSSCs).<sup>177–179</sup> Mali and co-workers prepared SnO<sub>2</sub> NFs and NBs with a smooth and uniform morphology as ETL *via* the electrospinning technique.<sup>168</sup> The pure tetragonal rutile phase in SnO<sub>2</sub> NFs and NBs was presented by structural analysis. SEM micrographs exhibited that both the lengths of SnO<sub>2</sub> NFs and NBs reached up to 500 μm with a diameter of about 450–500 nm and a thickness of 180–200 nm, respectively (Fig. 7b and c). Their optimized devices yielded a PCE of >16% based on SnO<sub>2</sub> NBs with good shelf-life stability.<sup>168</sup>

### 3.3 SnO<sub>2</sub> nanorods

Due to a particular open porous structure, SnO<sub>2</sub> nanorods (NRs) provide more expansive space to effectively fill the pores with the perovskite crystals<sup>180–183</sup> and enhance the light-induced photo utilization of the perovskite layer with good light scattering ability.<sup>184</sup>

Xu and co-workers reported good crystalline SnO<sub>2</sub> NRs as the ETL with a high aspect ratio through the sophisticated solvothermal approach to promote PSCs' stability and photovoltaic performance. They showed that oleic acid (OA) ligands could precisely control the length and the diameter of SnO<sub>2</sub> NRs without complex treatments. Besides, the insulating OA ligands had a weaker impact on the electron mobility of SnO<sub>2</sub> NRs than on TiO<sub>2</sub> NRs. The OA-capped SnO<sub>2</sub> NRs ETL-based PSCs with a planar structure achieved the best efficiency of over 18%, which was much higher than that of PSCs with an OA-capped TiO<sub>2</sub> NR ETL (14.27%).<sup>117</sup> Zhang *et al.* prepared the *in situ* SnO<sub>2</sub> NRs as ETL *via* a convenient hydrothermal method in an acidic solution.<sup>162</sup> The average diameters of SnO<sub>2</sub> NRs increased from 15 to 25 nm by controlling the precursor concentration, and the corresponding area density drops down to several hundreds of μm<sup>-2</sup>. Later on, to simplify the SnO<sub>2</sub> NR fabrication process and remove the OA ligand, Lv and co-workers reported a facile hydrothermal method to synthesize highly crystalline SnO<sub>2</sub> SRs with good light-harvesting ability (Fig. 7d). In the hydrothermal process, the reaction time and temperature are

vital process parameters that determine the morphology of SR, such as the length and the diameter. In addition, a TiO<sub>2</sub> inter-layer was inserted between the perovskite absorber layer and the SnO<sub>2</sub> ETL, forming a graded heterojunction configuration, leading to the power output of up to 18.7% with better ambient stability and repeatability.<sup>169</sup>

### 3.4 SnO<sub>2</sub> nanotubes

SnO<sub>2</sub> nanotubes (NTs) as ETL have higher conductivity and a required conduction band edge (3.6 eV) that can induce superior electrochemical properties than TiO<sub>2</sub> (3.2 eV) (Fig. 7e).<sup>185–188</sup> Gao and co-workers created SnO<sub>2</sub> NTs as ETL *via* an *in situ* template self-etching strategy. The ZnO<sub>2</sub> nanorods as sacrificial templates were covered by smooth nanoporous SnO<sub>2</sub> shells by spin coating. The corresponding EQE spectrum suggested that SnO<sub>2</sub> NTs based PSCs exhibited a high photocurrent of 15.9 mA cm<sup>-2</sup> with a stable efficiency of 12.1% in more than 1000 s under simulated light illumination.<sup>189</sup>

### 3.5 SnO<sub>2</sub> nanosheets

The SnO<sub>2</sub> nanosheets (NSs) demonstrate lots of advantages such as improving photo-induced carrier collection, promoting interfacial charge transfer, and processing good weathering performance of PSCs.<sup>163,171,190–192</sup>

Hydrothermal growth is a standard method to synthesize SnO<sub>2</sub> nanosheets. Zhou and co-workers prepared SnO<sub>2</sub> NSs as ETL *via* the hydrothermal method in place of the traditional mesoporous TiO<sub>2</sub> layer in PSCs for the first time (Fig. 7f). The device achieved a maximum efficiency of over 7% by optimizing the perovskite's crystallization time and treating it with TiCl<sub>4</sub> aqueous solution.<sup>171</sup> Liu and co-workers deposited a mesoporous layer of SnO<sub>2</sub> NSs on a thin, compact SnO<sub>2</sub> layer by using the low-temperature hydrothermal method to improve the PSC stability. The device with the highest efficiency of 16.17% was obtained through such a facile method and retained 90% of its initial PCE value in ambient after 130 d of storage without encapsulation.<sup>190</sup> To optimize the interfacial contact with the perovskite, doping with yttrium and introduction of a C<sub>60</sub> interlayer are done in SNS ETL-based devices. Yang and co-workers synthesized a yttrium-doped SnO<sub>2</sub> (Y-SnO<sub>2</sub>) as ETL *via* an *in situ* hydrothermal approach at 95 °C. As a result, the Y-SnO<sub>2</sub> based PSC achieved a champion PCE of 17.29% with free hysteresis.

Furthermore, it clearly showed that SnO<sub>2</sub> nanosheet films demonstrated a slightly wider bandgap and a more homogeneous distribution of SnO<sub>2</sub> nanosheet arrays after Y-doping.<sup>192</sup> The introduction of a C<sub>60</sub> interlayer (Y:SnO<sub>2</sub>) between SNS ETL and perovskite was reported by Wu.<sup>191</sup> They found that the C<sub>60</sub> interlayer can tune the energy level matching, reduce the charge accumulation and thus prolong the electron lifetime and enhance the V<sub>oc</sub>. The champion PCE obtained was 18.31%, and the device with C<sub>60</sub>-NSs preserved over 90% of its champion PCE after 500 h of storage at RT in open air.

### 3.6 SnO<sub>2</sub> quantum dots

Due to the low crystallinity, inferior electron mobility at lower annealing temperatures as well as instability of the SnO<sub>2</sub> film

deposited *via* colloidal SnO<sub>2</sub> solution, many researchers synthesized high-crystallinity SnO<sub>2</sub> quantum dots (QDs) as ETL by a facile mild solution method combined with spin coating on FTO to improve the light scattering and electron transport and reduce the charge recombination, leading to a dramatic increase in PCE.<sup>193–197</sup>

Yang and co-workers reported colloidal SnO<sub>2</sub> QDs as ETLs by a facile and repeatable two-step solution-processable method (Fig. 7g). First, they obtained the low concentration of SnO<sub>2</sub> QDs solution by controlling the amount of thiourea in the SnCl<sub>2</sub>·2H<sub>2</sub>O water solution, and then spin-coated SnO<sub>2</sub> QDs and changed the annealing temperature to eliminate a mass amount of thiol- and amino-groups, leading to an appropriate energy level matching and changeable carrier dynamics. Finally, the planar PSCs with SnO<sub>2</sub> QDs ETLs achieved a maximum power output of over 20% for the planar PSCs.<sup>93</sup> Vijayaraghavan and co-workers chose SnO<sub>2</sub> QDs as ETL to replace the commonly used mesoporous TiO<sub>2</sub> owing to their excellent electron extraction and hole blocking ability. For low-cost production and superior stability in air for PSCs, they designed the structure of glass/ITO/SnO<sub>2</sub> QDs/perovskite/carbon as HTL-free PSCs and deposited carbon electrodes *via* low-temperature curing to substitute the widely used vacuum-deposition. As a result, the highest power output of 13.64% was obtained.<sup>198</sup> Wang and co-workers used SnO<sub>2</sub> QDs as ETL, which was combined with potassium hexafluorophosphate (KPF6) treatment. KPF6 had the dual-passivation in which organic cation groups were reoriented or redistributed *via* the strong hydrogen bonds between the PF<sub>6</sub><sup>−</sup> group and organic cations. Moreover, KPF6 passivated the interfacial traps to suppress the energy level traps to improve the conductivity of SnO<sub>2</sub> through the solid ionic bonds between the PF<sub>6</sub><sup>−</sup> group and Sn<sup>4+</sup>/Sn<sup>2+</sup>.<sup>199</sup>

## 4. Passivation strategies of SnO<sub>2</sub> ETLs

Although SnO<sub>2</sub> films have several advantages over other metal oxide films, they also have comparable interface difficulties when used as the ETLs of PSCs. There are many flaws at the interfaces due to the bungle between the metal oxides and perovskite films, which degrade the presentation of PSCs. Therefore, passivations on the SnO<sub>2</sub> film are often used to improve the performance of SnO<sub>2</sub> based perovskite solar cells that include elemental doping, bilayer design, and interface modification. The following are the consequences on passivation: (1) tuning of the energy level that promotes electron transfer at the ETL/perovskite interface; (2) passivation of the interfacial defects and suppress nonradiative recombination; (3) control of the crystallization process and improvement of the crystallinity of the perovskite film; and (4) endowing devices with improved humidity tolerance and long-term stability.

### 4.1 Elemental doping

Owing to intrinsic defects such as Sn interstitials or O vacancies, there is serious charge recombination and contact resistance at the interface between SnO<sub>2</sub> ETL and perovskite, resulting in a low charge transportation rate.<sup>200–203</sup> To suppress the traps on the SnO<sub>2</sub> film as well as for better energy-level alignment, the researchers demonstrated several halides and metal ions as dopants to improve the conductivity properties of ETL including the halogen ions (Cl<sup>−</sup><sup>204–206</sup> and F<sup>−</sup><sup>207–211</sup>), metal ions (Li<sup>+</sup><sup>212–215</sup> Mg<sup>2+</sup><sup>196,216</sup> Al<sup>3+</sup><sup>217,218</sup> Zn<sup>2+</sup><sup>143,219</sup> Sb<sup>3+</sup><sup>215,220,221</sup> Mo<sup>2+</sup><sup>222</sup> Ru<sup>2+</sup><sup>209,223</sup> Ga<sup>3+</sup><sup>224,225</sup> Zr<sup>2+</sup><sup>226,227</sup> Nb<sup>5+</sup><sup>228–230</sup> and Ta<sup>5+</sup><sup>231</sup>) and rare earth ions (Y<sup>3+</sup><sup>192,232</sup> La<sup>3+</sup><sup>233</sup>) and Nd<sup>3+</sup><sup>165</sup> (Table 2).

Gong and co-workers introduced Cl in SnO<sub>2</sub> nanoparticles (SnO<sub>2</sub>–Cl) with a chloroform-D/2-methoxy ethanol solvent (Fig. 8a).<sup>205</sup> The SnO<sub>2</sub>–Cl film had a hydrophobic surface as the

Table 2 Representative PSCs based on elemental doped SnO<sub>2</sub> ETL

| Doped element    | Doping raw material                                  | Device architecture  | Perovskite   | PCE (%) | Ref. |
|------------------|--|--|--|---------|------|
| Cl <sup>−</sup>  | Chloroform-D/2-methoxy ethanol solvent               | FTO/Cl–SnO <sub>2</sub> /perovskite/spiro-OMeTAD/Au                                  | (FAPbI <sub>3</sub> ) <sub>0.85</sub> (MAPbBr <sub>3</sub> ) <sub>0.15</sub>   | 18.1    | 205  |
| F <sup>−</sup>   | NH <sub>4</sub> F                                    | FTO/F–SnO <sub>2</sub> /perovskite/spiro-OMeTAD/Au                                   | (FAPbI <sub>3</sub> ) <sub>0.85</sub> (MAPbBr <sub>3</sub> ) <sub>0.15</sub>   | 20.2    | 207  |
| Li <sup>+</sup>  | Li-TFSI  | FTO/SnO <sub>2</sub> /Al <sub>2</sub> O <sub>3</sub> /perovskite/spiro-OMeTAD/carbon | MAPbI <sub>3</sub>   | 10.01   | 214  |
| Mg <sup>2+</sup> | MgAc·4H <sub>2</sub> O                               | FTO/Mg–SnO <sub>2</sub> /perovskite/spiro-OMeTAD/Au                                  | MAPbI <sub>3</sub>   | 19.21   | 196  |
| Al <sup>3+</sup> | Al(NO <sub>3</sub> ) <sub>3</sub>                    | FTO/Al–SnO <sub>2</sub> /perovskite/spiro-OMeTAD/Au                                  | Cs <sub>0.05</sub> (MA <sub>0.17</sub> FA <sub>0.83</sub> ) <sub>0.95</sub> Pb(I <sub>0.83</sub> Br <sub>0.17</sub> ) <sub>3</sub> | 17.66   | 218  |
| Zn <sup>2+</sup> | ZnCl <sub>2</sub>                                    | FTO/ZnSnO <sub>2</sub> /perovskite/CuPc/carbon                                       | Cs <sub>0.05</sub> FA <sub>0.79</sub> MA <sub>0.16</sub> PbI <sub>2.5</sub> Br <sub>0.5</sub>                                      | 17.78   | 143  |
| Sb <sup>3+</sup> | SbCl <sub>3</sub>                                    | ITO/Sb–SnO <sub>2</sub> /perovskite/spiro-OMeTAD/Au                                  | Cs <sub>0.05</sub> (FA <sub>0.85</sub> MA <sub>0.15</sub> ) <sub>0.95</sub> Pb(I <sub>0.85</sub> Br <sub>0.15</sub> ) <sub>3</sub> | 20.73   | 221  |
| Mo <sup>5+</sup> | MoCl <sub>5</sub>                                    | FTO/Mo–SnO <sub>2</sub> /perovskite/spiro-OMeTAD/Au                                  | MAPbI <sub>3</sub>   | 10.52   | 222  |
| Ru <sup>2+</sup> | RuCl <sub>3</sub> ·5H <sub>2</sub> O                 | FTO/Ru–SnO <sub>2</sub> /perovskite/spiro-OMeTAD/Au                                  | Cs <sub>0.05</sub> (MA <sub>0.10</sub> FA <sub>0.90</sub> ) <sub>0.95</sub> Pb(I <sub>0.90</sub> Br <sub>0.10</sub> ) <sub>3</sub> | 22.0    | 223  |
| Ga <sup>3+</sup> | Ga(NO <sub>3</sub> ) <sub>3</sub> ·6H <sub>2</sub> O | ITO/Ga–SnO <sub>2</sub> /perovskite/spiro-OMeTAD/Ag                                  | (FAPbI <sub>3</sub> ) <sub>0.97</sub> (MAPbBr <sub>3</sub> ) <sub>0.03</sub>   | 18.18   | 224  |
| Zr <sup>2+</sup> | ZrCl <sub>2</sub> ·8H <sub>2</sub> O                 | ITO/Zr–SnO <sub>2</sub> /perovskite/spiro-OMeTAD/Au                                  | (FAPbI <sub>3</sub> ) <sub>0.85</sub> (MAPbBr <sub>3</sub> ) <sub>0.15</sub>   | 19.54   | 226  |
| Nb <sup>5+</sup> | NbCl <sub>5</sub>                                    | FTO/Nb–SnO <sub>2</sub> /perovskite/spiro-OMeTAD/Au                                  | FA <sub>0.75</sub> MA <sub>0.2</sub> Cs <sub>0.05</sub> Pb(I <sub>0.14</sub> Br <sub>0.86</sub> ) <sub>3</sub>                     | 20.5    | 228  |
| Ta <sup>5+</sup> | TaCl <sub>5</sub>                                    | ITO/Ta–SnO <sub>2</sub> /perovskite/spiro-OMeTAD/Au                                  | Cs <sub>0.05</sub> (MA <sub>0.10</sub> FA <sub>0.90</sub> ) <sub>0.95</sub> Pb(I <sub>0.90</sub> Br <sub>0.10</sub> ) <sub>3</sub> | 20.8    | 231  |
| Y <sup>3+</sup>  | Y(OC <sub>4</sub> H <sub>9</sub> ) <sub>3</sub>      | FTO/Y–SnO <sub>2</sub> /perovskite/spiro-OMeTAD/Au                                   | Cs <sub>0.05</sub> (MA <sub>0.15</sub> FA <sub>0.85</sub> ) <sub>0.95</sub> Pb(I <sub>0.85</sub> Br <sub>0.15</sub> ) <sub>3</sub> | 20.71   | 232  |
| La <sup>3+</sup> | LaCl <sub>3</sub> ·5H <sub>2</sub> O                 | FTO/La–SnO <sub>2</sub> /perovskite/spiro-OMeTAD/Au                                  | MAPbI <sub>3</sub>   | 17.08   | 233  |
| Nd <sup>3+</sup> | Nd(NO <sub>3</sub> ) <sub>3</sub> ·6H <sub>2</sub> O | FTO/Nd–SnO <sub>2</sub> /perovskite/spiro-OMeTAD/Au                                  | Cs <sub>0.05</sub> (MA <sub>0.17</sub> FA <sub>0.83</sub> ) <sub>0.95</sub> Pb(I <sub>0.83</sub> Br <sub>0.17</sub> ) <sub>3</sub> | 20.92   | 165  |

effect of Cl, which increased the grain size of perovskite crystals (Fig. 9). Furthermore,  $\text{SnO}_2\text{-Cl}$  as an ETL dramatically reduced the electron trap density and inhibited the charge recombination. In contrast to untreated  $\text{SnO}_2$  based PSCs,  $\text{SnO}_2\text{-Cl}$  based PSCs achieved a PCE of 18.1%, with significant improvements in  $J_{\text{sc}}$  and reduced hysteresis. Later, Wang *et al.* reported F-doped  $\text{SnO}_2$  (F: $\text{SnO}_2$ ) nanocrystals as the ETL by spin-coating  $\text{SnCl}_2 \cdot 2\text{H}_2\text{O}$  and  $\text{NH}_4\text{F}$  solution onto fresh FTO substrates in a facile solution-processable method at low temperatures (Fig. 8b).<sup>207</sup> They found that the band offset between the ETL and the perovskite absorber is related to the F doping level in  $\text{SnO}_2$  nanocrystals; the band offset was effectively tailored by doping F into the  $\text{SnO}_2$  film, which led to an increasing built-in electric field for maximizing the  $V_{\text{oc}}$  and charge collection simultaneously. Consequently, a champion PCE of 20.2% with a  $V_{\text{oc}}$  of 1.13 V can be obtained for n-i-p planar PSCs using an F-doped  $\text{SnO}_2$  bilayer ETL.

Jung and coworkers reported doped  $\text{SnO}_2$  NPs by Zr element, improving the multiple optoelectronic properties of  $\text{SnO}_2$  (Fig. 8c). Zr doping reduced the current leakage and suppressed the charge recombination, facilitating the interfacial transfer between the ETL and the perovskite layer. Consequently, they obtained the best PCE of 19.54% with reduced hysteresis. The research demonstrated that the controlled Zr-doping  $\text{SnO}_2$  film

led to adjusted energy levels, increased electrical conductivities, and decreased surface defect densities for optimal interface properties of PSCs.<sup>226</sup> Some other elements also showed similar positive results.<sup>209,214,223,231</sup>

Fang and co-workers designed a Zr/F co-doped  $\text{SnO}_2$  ETL due to its low conduction band position and limited intrinsic carriers; they found that the doping of Zr can increase the CB of  $\text{SnO}_2$  for higher  $V_{\text{oc}}$ , which decreased the energy traps in electron extraction and restrained the interface recombination between the ETL and the perovskite (Fig. 8d). Moreover, as n-type doping, F doping endowed  $\text{SnO}_2$  with a mass of free electrons and facilitated the conductivity of the ETL for improvement in short-circuit current ( $J_{\text{sc}}$ ). With the merits of Zr/F co-doping, the device boosted the PCE by over 19% with free hysteresis, which surpassed the undoped device. This result demonstrated the effect of Zr/F co-doping on the regulation of energy level match and conductivity of  $\text{SnO}_2$ .<sup>234</sup>

## 4.2 Bilayer ETLs

A mass of pinholes and cracks appear in the  $\text{SnO}_2$  film during the fabrication process. The traps reduce the current leakage energy and retard the carrier transfer at the interface, resulting in current leakage in PSCs and a poor photovoltaic

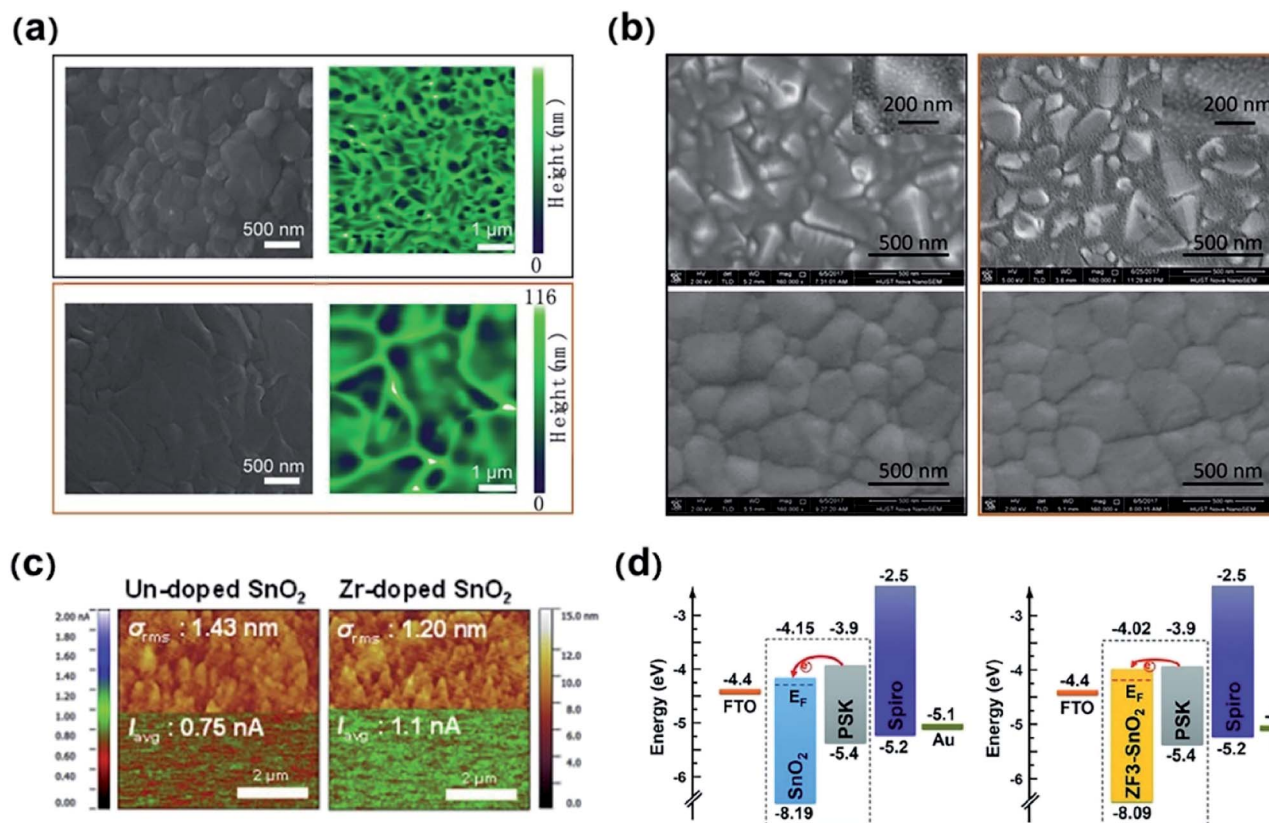


Fig. 8 (a) Top view SEM images and AFM images of perovskite films on (up) FTO/ $\text{SnO}_2$  and (down) FTO/ $\text{SnO}_2\text{-Cl}$ . Reproduced with permission.<sup>205</sup> Copyright 2020, Royal Society of Chemistry. (b) SEM images of (left)  $\text{SnO}_2$  and its perovskite (right) F: $\text{SnO}_2$  and its perovskite. Reproduced with permission.<sup>207</sup> Copyright 2020, ACS Publishing Group. (c and a) AFM and c-AFM images (bottom) of  $\text{SnO}_2$  NPs thin films with and without Zr-doping. Reproduced with permission.<sup>226</sup> Copyright 2019, Elsevier. (d) Schematic of the energy level arrangement for the pristine  $\text{SnO}_2$  device and the Zn/F doped- $\text{SnO}_2$  device. Reproduced with permission.<sup>234</sup> Copyright 2020, Wiley-VCH.

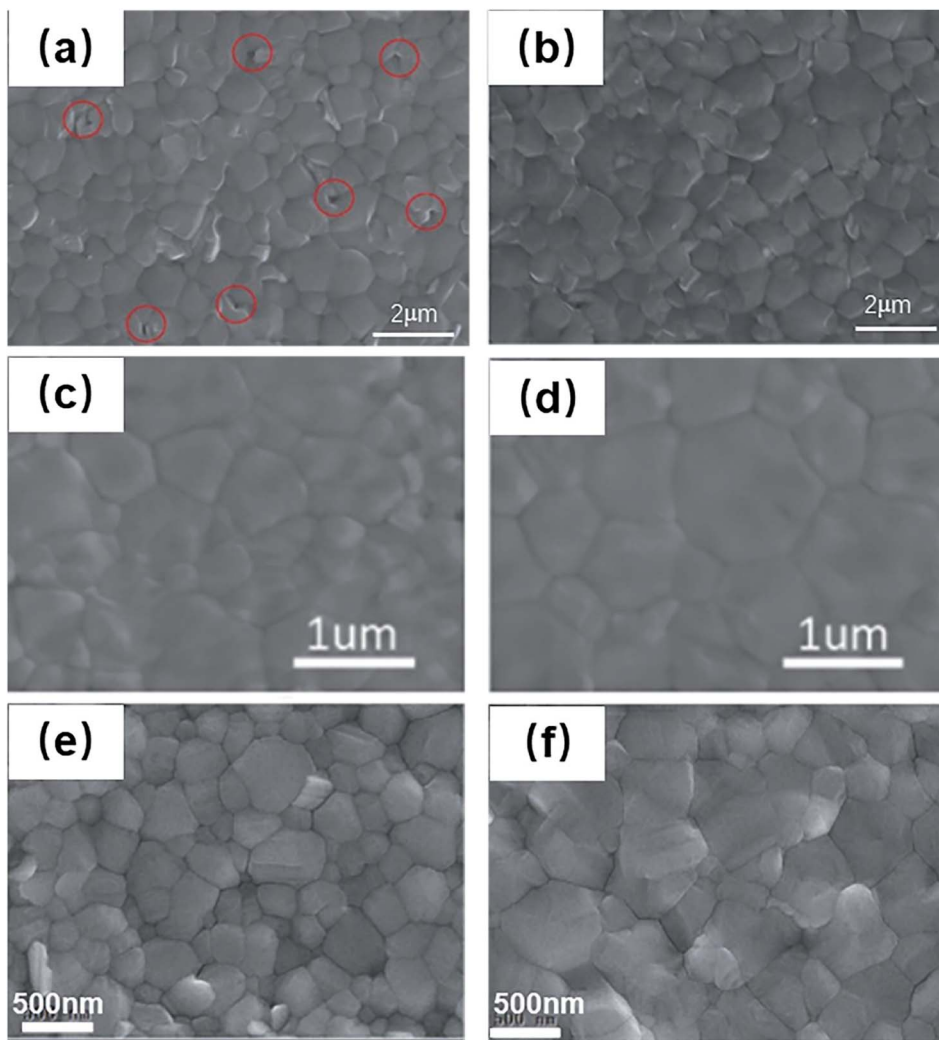


Fig. 9 Top-view SEM images of perovskite films deposited on SnO<sub>2</sub> and SnO<sub>2</sub>/metal oxide ETLs. (a) SnO<sub>2</sub> and (b) In<sub>2</sub>O<sub>3</sub>/SnO<sub>2</sub>. Reproduced with permission.<sup>245</sup> Copyright 2020, Wiley-VCH. (c) SnO<sub>2</sub>; (d) WO<sub>x</sub>/SnO<sub>2</sub>. Reproduced with permission.<sup>246</sup> Copyright 2019, Elsevier B.V. (e) P-SnO<sub>2</sub>; (f) B-SnO<sub>2</sub>. Reproduced with permission.<sup>247</sup> Copyright 2021, Wiley-VCH.

performance. Bilayer ETLs based on SnO<sub>2</sub> films combined with a thin layer of metal oxide (*i.e.* TiO<sub>2</sub>,<sup>235,236</sup> Al<sub>2</sub>O<sub>3</sub>,<sup>214,237</sup> Ga<sub>2</sub>O<sub>3</sub>,<sup>238</sup> ZnO,<sup>239–242</sup> SnO<sub>2</sub><sup>122,221</sup> and ZnTiO<sub>3</sub><sup>243</sup>) or organic transporting materials (PCBM and C<sub>60</sub>) are used to suppress the interface and bulk defects and charge recombination.

**4.2.1 SnO<sub>2</sub>/metal oxide ETLs.** In n-i-p PSC devices, bilayers of metal oxide composite structures are massively used as ETLs. For example, considering the advantages of the high electron mobility of SnO<sub>2</sub> ( $\approx 10^{-3}$  cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup>) compared with that of TiO<sub>2</sub> ( $\approx 10^{-5}$  cm<sup>2</sup> V<sup>-1</sup> s<sup>-1</sup>) and the high reproducibility of TiO<sub>2</sub> ETLs, Mali and co-workers selected SnO<sub>2</sub> coated c-TiO<sub>2</sub> bilayer ETLs. Owing to its high conductivity, SnO<sub>2</sub> occupied the defect sites, which can suppress the surface traps of the TiO<sub>2</sub> film, leading to efficient electron extraction from the perovskite absorber. Meanwhile, the high mobility of the SnO<sub>2</sub> interfacial layer played a role in maintaining the charge balance of the PSC.<sup>244</sup>

Wang and co-workers reported a convenient low-temperature process to prepare an In<sub>2</sub>O<sub>3</sub>/SnO<sub>2</sub> bilayer as the

ETL (Fig. 9a and b). The introduction of In<sub>2</sub>O<sub>3</sub> was beneficial to the formation of smooth, dense, and low-defect-density perovskite films. Besides, the CB of In<sub>2</sub>O<sub>3</sub> was lower than that of Sn-doped In<sub>2</sub>O<sub>3</sub> (ITO), facilitating the charge transfer at the interface between perovskite and the ETL, thus reducing the  $V_{oc}$  loss. The device with a PCE of over 23% was achieved, and a high  $V_{oc}$  of 1.17 V was obtained with the potential loss (0.36 V). Additionally, the PSC retained 97.5% initial PCE after 80 days in a N<sub>2</sub> atmosphere without encapsulation and maintained 91% of its original PCE after 180 h under 1 AM illumination.<sup>245</sup>

Wang and co-workers proposed an amorphous WO<sub>x</sub>/SnO<sub>2</sub> hybrid ETL to effectively block holes through the defects of the SnO<sub>2</sub> film to ITO, thereby promoting the charge extraction and reducing the electron-hole recombination at the interface (Fig. 9c and d). Moreover, due to the appropriate energy-level alignment and high conductivity, they also obtained better electron transfer channels. In contrast to flexible PSCs with a single SnO<sub>2</sub> ETL, the PSCs with an amorphous WO<sub>x</sub>/SnO<sub>2</sub>

hybrid ETL showed a better PCE of 20.52%. Moreover, the  $\text{WO}_x/\text{SnO}_2$  preparation process was at a temperature below 150 °C.<sup>246</sup>

Ye and co-workers proposed a bilayer ETL consisting of two different  $\text{SnO}_2$  films at a low temperature (70 °C), combined with various amounts of  $\text{NH}_4\text{Cl}$  as additives (Fig. 9e and f). The novel  $\text{SnO}_2$  bilayer tuned the bandgap alignment at the  $\text{SnO}_2$ /perovskite interface and reduced strain in the perovskite film growth, which resulted in negligible carrier recombination, high conductivity, and low voltage loss. Finally, the best device with a doped  $\text{SnO}_2$  bilayer ETL achieved a photovoltaic performance of 21.75% and strongly increased the  $V_{\text{oc}}$  up to 1.21 V with negligible hysteresis.<sup>247</sup>

**4.2.2  $\text{SnO}_2$ /fullerene derivative ETLs.** Fullerene and its derivatives with efficient charge extraction are commonly used as the ETL in p-i-n planar PSCs, including  $\text{C}_{60}$  and phenyl- $\text{C}_{61}$ -butyric acid methyl ester ( $\text{PC}_{61}\text{BM}$ ).<sup>157,248–257</sup> Owing to the drawbacks of  $\text{SnO}_2$  in inefficient charge extraction and interfacial charge recombination, many researchers have tried to deposit the  $\text{SnO}_2$  film combined with fullerenes or its derivatives as a bilayer to eliminate the issues in achieving efficient and stable PSCs.

Tian and co-workers used 2,5-diphenyl- $\text{C}_{60}$ -fulleropyrrolidine ( $\text{DPC}_{60}$ ) to passivate the defects on the  $\text{SnO}_2$  film surface, forming a  $\text{SnO}_2/\text{DPC}_{60}$  bilayer structure as the ETL in PSCs (Fig. 10a, b and c).  $\text{DPC}_{60}$  can reduce charge

recombination in the interface of  $\text{SnO}_2$ /perovskite and offer an appropriate band edge alignment, which led to electron transfer from the perovskite absorber to the FTO electrode. As a result, this reveals that electron extraction can be improved *via* modification on the perovskite/ $\text{SnO}_2$  interface with ( $\text{DPC}_{60}$ ). The PCE of 20.4% was obtained for PSCs based on the  $\text{SnO}_2/\text{DPC}_{60}$  bilayer, which was higher than that of 18.8% PSCs based on a single  $\text{SnO}_2$  film.<sup>258</sup>

Later on, Raiford and co-workers reported an ultrathin (2 nm) layer of polyethyleneimine ethoxylate (PEIE) to functionalize the surface of  $\text{C}_{60}$  for the subsequent preparation of  $\text{SnO}_2$  by ALD as an electron contact bilayer for p-i-n PSCs. They first used Auger electron spectroscopy (AES) mapping to shed light on the effect of PEIE on  $\text{SnO}_2$  nucleation in  $\text{C}_{60}$ . Through a series of testing conditions in the air atmosphere with simultaneous stressors of heat and illumination, improved nucleation contributed to more stable PSCs. These devices got a high initial PCE of 18.5% with 40% improvement in stability over devices with  $\text{C}_{60}/\text{SnO}_2$  contacts without modification with PEIE following a continuous operation at 60 °C unencapsulated in the ambient environment for 250 h.<sup>259</sup>

In recent, Palmstrom and co-workers investigated the impacts of  $\text{SnO}_2$  on the perovskite film and explored the role of  $\text{C}_{60}$  as an organic electron extractor at the interface. Furthermore, they offered strategies to remove the  $\text{C}_{60}$  layer at the perovskite/ $\text{SnO}_2$

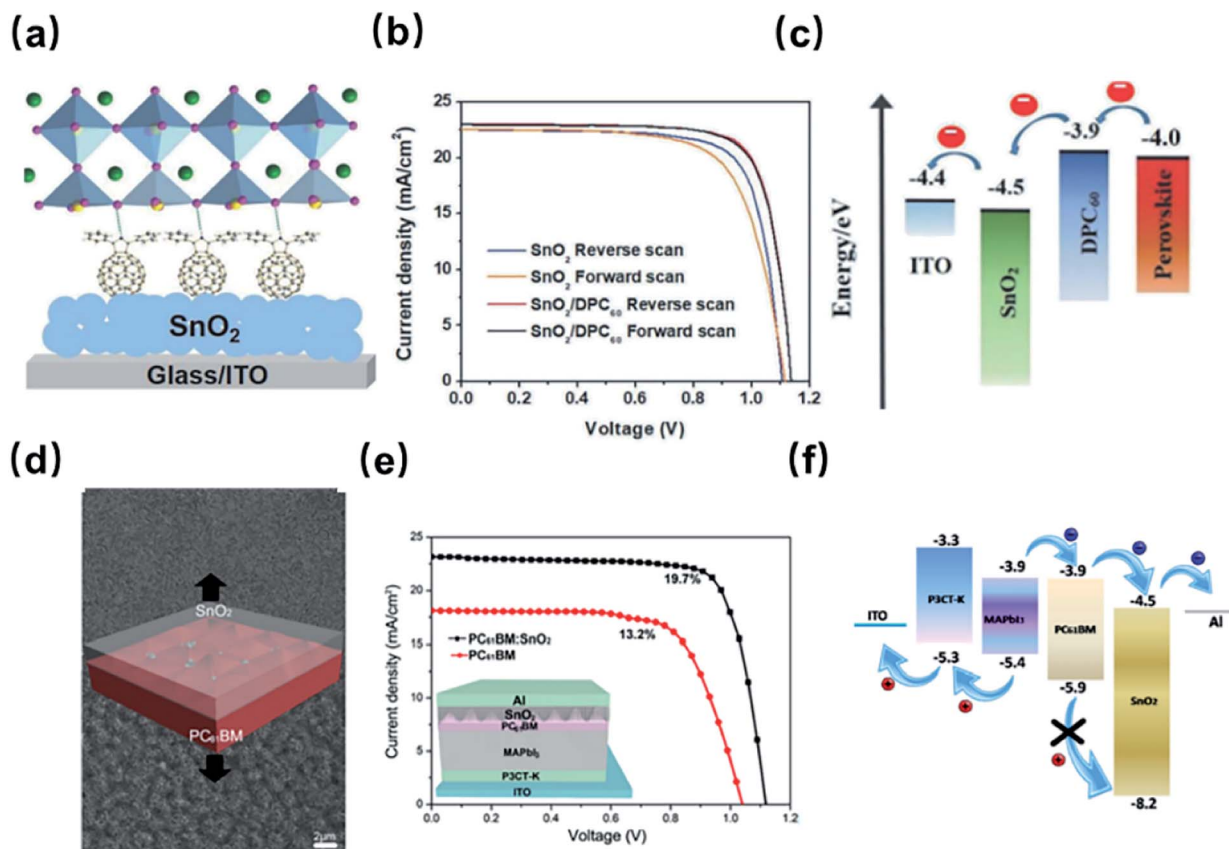


Fig. 10 (a and d) Illustrations of the interfacial treatment. (b and e) Forward and reverse scan  $J$ - $V$  curves of devices with and without interfacial modification. (c and f) Energy band diagram of PSCs; (a–c) Reproduced with permission.<sup>258</sup> Copyright 2020, Wiley-VCH. (d–f) Reproduced with permission.<sup>265</sup> Copyright 2018, ACS Publishing Group.

interface.<sup>260</sup> Organic extraction layers reduced the mechanical strength and endowed the perovskite/C<sub>60</sub> interface with mechanical defects in PSCs.<sup>261,262</sup> Owing to the high fabrication cost and poor mechanical stability of C<sub>60</sub>, PCBM is desirable to reduce the need for the organic layer in future devices.

In addition to regular PSCs, SnO<sub>2</sub> is used in inverted PSCs as bilayers with organic transport materials, which preserve efficient electron transport and improve ambient stability. Zhu *et al.* first used the hydrothermal method to create highly crystalline SnO<sub>2</sub> nanocrystals (NCs) that could be used as an efficient ETL in conjunction with C<sub>60</sub>. The best device, owing to its high crystallinity and hydrophobicity, achieves a high PCE of 18.8% and retains more than 90% of its initial PCE after 30 days of storage in an ambient environment with >70% relative humidity.<sup>127</sup> Similarly, Liu used HClO<sub>4</sub> to control crystallization during the SnO<sub>2</sub> deposition process. Based on the SnO<sub>2</sub>/C<sub>60</sub> bilayer, the unencapsulated inverted PSCs had a champion PCE of more than 16% and retained more than 80% of its initial PCE value after 90 days (>2100 h) of storage in an air atmosphere.<sup>263</sup> Luo *et al.* reported carbon nanotube films coated with SnO<sub>2</sub> (SnO<sub>2</sub>@CSCNT) as ETL in the application of inverted CH<sub>3</sub>NH<sub>3</sub>-PbI<sub>3</sub>/NiO PSCs and achieved the best PCE of 14.3% with better stability under a high humidity, thermal stress, or continuous light soaking condition.<sup>264</sup>

Wang and colleagues used a PC<sub>61</sub>BM:SnO<sub>2</sub> bilayer as the ETL in inverted PSCs and achieved a high PCE of 19.7% (Fig. 10d, e and f). The device with the PC<sub>61</sub>BM:SnO<sub>2</sub> bilayer outperformed the device based on a single PC<sub>61</sub>BM ETL by 49.0%. The SEM revealed smooth and compact PC<sub>61</sub>BM:SnO<sub>2</sub> layers with minor pinholes and cracks, promoting electron transfer and reducing charge recombination. Furthermore, the device's stability was improved over the PC<sub>61</sub>BM-only device (Table 3).<sup>265</sup>

### 4.3 Interface modification

Although SnO<sub>2</sub> has excellent optoelectronic properties, defects or traps appear in SnO<sub>2</sub> films because of improper deposition methods, which will become the center of carrier recombination, resulting in decreased PCE. UV treatment is a common way to remove surface impurities or residuals, suppress the oxygen vacancies, and facilitate surface wettability for perovskite film growth.<sup>102,266–269</sup> To improve the film quality, reduce the surface defects, and facilitate interfacial contact, many researchers introduced a series of materials to passivate interfacial defects and promote the conductivity of the SnO<sub>2</sub> film, which are all very significant to achieve an efficient and stable PSC device,

including ammonium salts, quantum dots, self-assembled monolayers, 2D materials, and carbon materials.

**4.3.1 Ammonium salts.** Despite its high electron mobility, SnO<sub>2</sub> ETL deposited at a low temperature suffers from poor film crystallinity and large defect density, which usually reduce the PSC efficiency. Ammonium salts are introduced for SnO<sub>2</sub> surface modification to reduce the interfacial defects.<sup>97,247,270,271</sup>

Chen and co-workers introduced Girard's Reagent T (GRT) into the SnO<sub>2</sub> NP colloidal solution and obtained a high efficiency of 21.63% with free hysteresis. The AFM and contact angle test results showed better roughness and wettability for the SnO<sub>2</sub> film with GRT modification due to the chemical interaction between GRT and SnO<sub>2</sub> NPs (Fig. 11a and b). As a result, the quality of perovskite films with GRT modification was also improved. Many holes could be effectively eliminated in the perovskite film compared with the control ones. The vertically oriented large grains were across the whole cross-section, which confirmed that GRT modification is beneficial to the SnO<sub>2</sub> NP dispersion and the interfacial contact between the ETL and the perovskite layer.<sup>97</sup>

Jung and co-workers used ammonium fluoride (NH<sub>4</sub>F) to modify the SnO<sub>2</sub> surface to eliminate trap sites and change the Fermi level of SnO<sub>2</sub> thin films (Fig. 11c and d). They suggested that an ammonium cation in NH<sub>4</sub>F generated ammonia gas and water vapor due to the reaction with hydroxyls on the SnO<sub>2</sub> surface. Besides, fluoride anions would get inserted into the trap sites, resulting in an adjustment of the energy level. PSCs with treated SnO<sub>2</sub> achieved a champion performance of 23.2%.<sup>272</sup>

Huang *et al.* showed that the addition of the IL tetramethylammonium hydroxide N(CH<sub>3</sub>)<sub>4</sub>OH (TMAH) to the SnO<sub>2</sub> nanoparticle suspension to form a stable and homogeneous suspension could result in a better SnO<sub>2</sub> ETL with lower defect density and higher conductivity for a better FF (Fig. 11e and f).<sup>273</sup> As a result, TMAH-SnO<sub>2</sub>-based PSCs showed a higher PCE (20.28%) than that of non-treated SnO<sub>2</sub>-based PSCs (18.14%). Ethylenediaminetetraacetic acid (EDTA) is introduced onto SnO<sub>2</sub> to increase the electron mobility of the ETLs, resulting in a PCE of 21.60% and a certified PCE reaching 21.52%.<sup>274</sup>

**4.3.2 Quantum dots (QDs).** The quantum dots (QDs) had a tunable bandgap together with the quantum confinement and edge effects, which were novel promising zero-dimensional materials to decorate the SnO<sub>2</sub> surface to promote the electron conduction of SnO<sub>2</sub>.<sup>103,275</sup>

Chen and co-workers developed a SnO<sub>2</sub>/graphitic carbon nitride quantum dot (g-C<sub>3</sub>N<sub>4</sub> QD) nanocomposite (G-SnO<sub>2</sub>) as

Table 3 Representative PSCs based on bilayer ETLs

| Bilayer  | Depositor method           | $J_{SC}$ (mA cm <sup>-2</sup> ) | $V_{oc}$ (V) | FF (%) | PCE (%) | Ref. |
|--|----------------------------|---------------------------------|--------------|--------|---------|------|
| SnO <sub>2</sub> /In <sub>2</sub> O <sub>3</sub> | Spin-coating               | 24.45                           | 1.17         | 87.09  | 23.24   | 245  |
| SnO <sub>2</sub> /a-WO <sub>x</sub>              | Vacuum thermal evaporation | 23.01                           | 1.11         | 80.34  | 20.52   | 246  |
| L-SnO <sub>2</sub> /H-SnO <sub>2</sub>           | Spin-coating               | 23.6                            | 1.21         | 76.2   | 21.75   | 247  |
| SnO <sub>2</sub> /DPC <sub>60</sub>              | Spin-coating               | 23                              | 1.14         | 77.7   | 20.4    | 258  |
| SnO <sub>2</sub> /C <sub>60</sub> with PEIE      | Vacuum thermal evaporation | 19.66                           | 1.154        | 81.8   | 18.5    | 259  |
| SnO <sub>2</sub> /PC <sub>61</sub> BM            | Spin-coating               | 23.15                           | 1.12         | 76     | 19.7    | 265  |



the functional ETL to accurately control the interfacial charge dynamics of efficient n-i-p planar PSCs (Fig. 12a, b and c). The  $g\text{-C}_3\text{N}_4$  QDs could suppress the oxygen-vacancy-induced traps and facilitate the interfacial charge transfer by redistributing the electronic density around the neighboring  $\text{SnO}_2$  crystal unit, resulting in enhanced electrical properties, appropriate

bandgap matching and high electron conduction. Employing the  $\text{SnO}_2/g\text{-C}_3\text{N}_4$  QDs-based ETL, a champion PCE of 22.13% can be obtained with negligible hysteresis and long-term stability.<sup>276</sup>

Hui and co-workers recently reported carboxylic-acid- and hydroxyl-rich red-carbon quantum dot (RCQ) modified- $\text{SnO}_2$

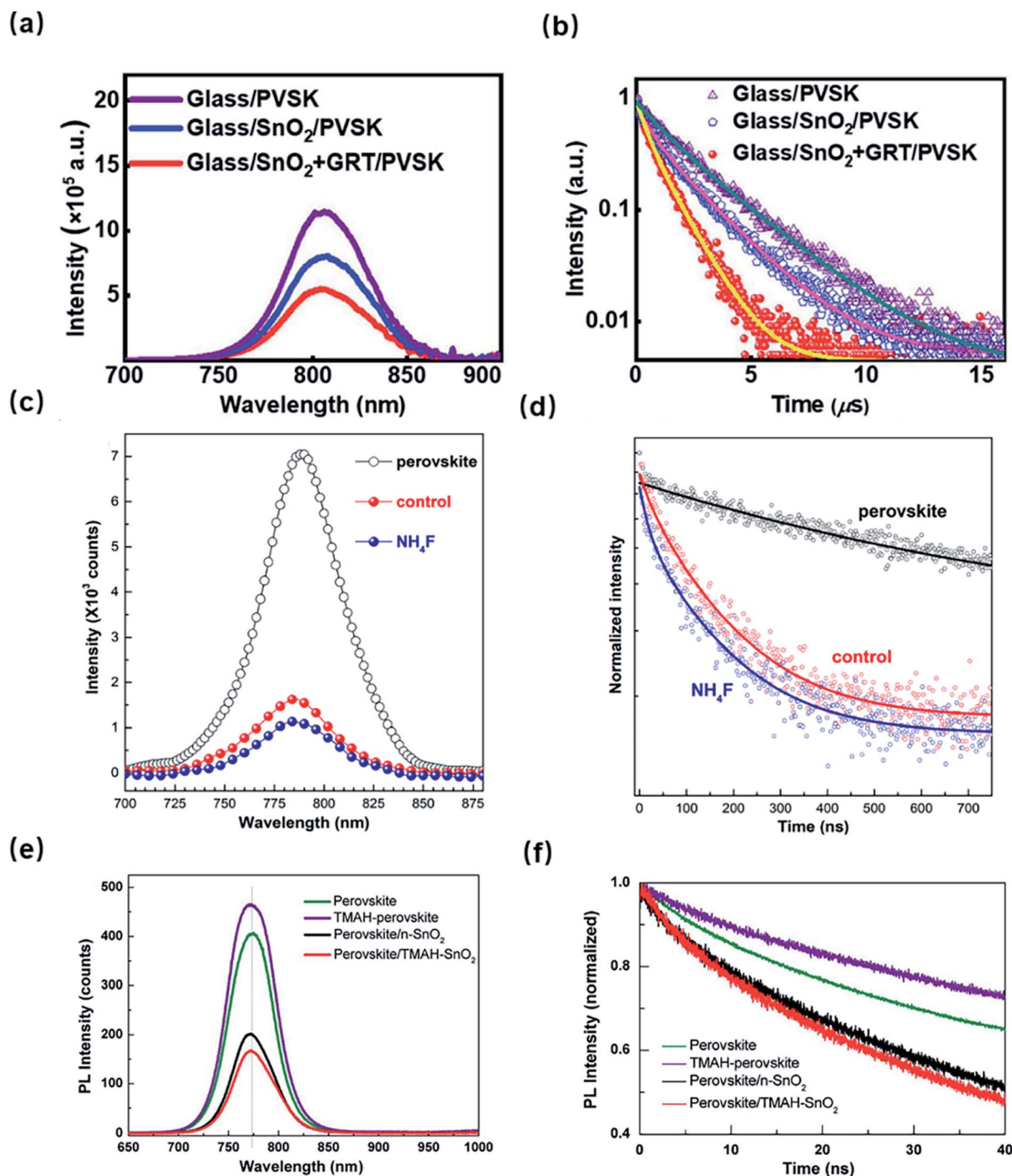


Fig. 11 Steady-state PL spectra of the perovskite film deposited on: (a)  $\text{SnO}_2$  and GRT- $\text{SnO}_2$ , (c)  $\text{SnO}_2$  and  $\text{NH}_4\text{F}$ - $\text{SnO}_2$ , (e)  $\text{SnO}_2$  and TMAH- $\text{SnO}_2$ . Normalized time-resolved PL: (b)  $\text{SnO}_2$  and GRT- $\text{SnO}_2$  ETLs, (d)  $\text{SnO}_2$  and  $\text{NH}_4\text{F}$ - $\text{SnO}_2$  ETLs, and (f)  $\text{SnO}_2$  and TMAH- $\text{SnO}_2$ . (a and b) Reproduced with permission.<sup>97</sup> Copyright 2021, Royal Society of Chemistry. (c and d) Reproduced with permission.<sup>272</sup> Copyright 2020, ACS Publishing Group. (e and f) Reproduced with permission.<sup>273</sup> Copyright 2018, Royal Society of Chemistry.

with a suitable band alignment (Fig. 12d, e and f). The calculated electron mobility of SnO<sub>2</sub>-RCQs by using the space charge-limited current (SCLC) model was increased by 2 orders of magnitudes, resulting in a significant reduction in the conductivity of SnO<sub>2</sub>-RCQs. Simultaneously, the RCQ modified SnO<sub>2</sub> layer not only passivated the ETL/perovskite interface but also facilitated the crystallinity of the perovskite film, with dense and smooth morphology over a large area. This device with modified SnO<sub>2</sub> obtained an outstanding efficiency of 22.77% with negligible hysteresis and showed long-term stability against moisture, maintaining over 95% of the original PCE value after 1000 h storage in an ambient environment.<sup>277</sup>

Xie and co-workers added graphene quantum dots (GQDs) to the SnO<sub>2</sub> precursor to form a SnO<sub>2</sub>:GQDs layer as the ETL by

a simple spin-coating method (Fig. 12g, h and i). It was found that GQDs effectively promoted electron transport and passivated the electron traps at the interface, which led to improved electron extraction rate and reduced charge accumulation at the ETL/perovskite interface. As a consequence, the best device based on SnO<sub>2</sub>:GQDs ETLs exhibited a PCE of 20.23% and a free hysteresis effect.<sup>269</sup>

**4.3.3 Self-assembled monolayers (SAMs).** Like commonly used metal oxides such as TiO<sub>2</sub>, SnO<sub>2</sub>, ZnO, MoO<sub>x</sub>, or organic charge transport molecules such as PC<sub>61</sub>BM and poly(3,4-ethylenedioxy-thiophene)polystyrene (PEDOT:PSS), SnO<sub>2</sub> has hydroxyl groups at the surface of the film, and they cause defects states near the valence band, which can induce a non-radiative recombination at the SnO<sub>2</sub>/perovskite interface.<sup>278</sup>

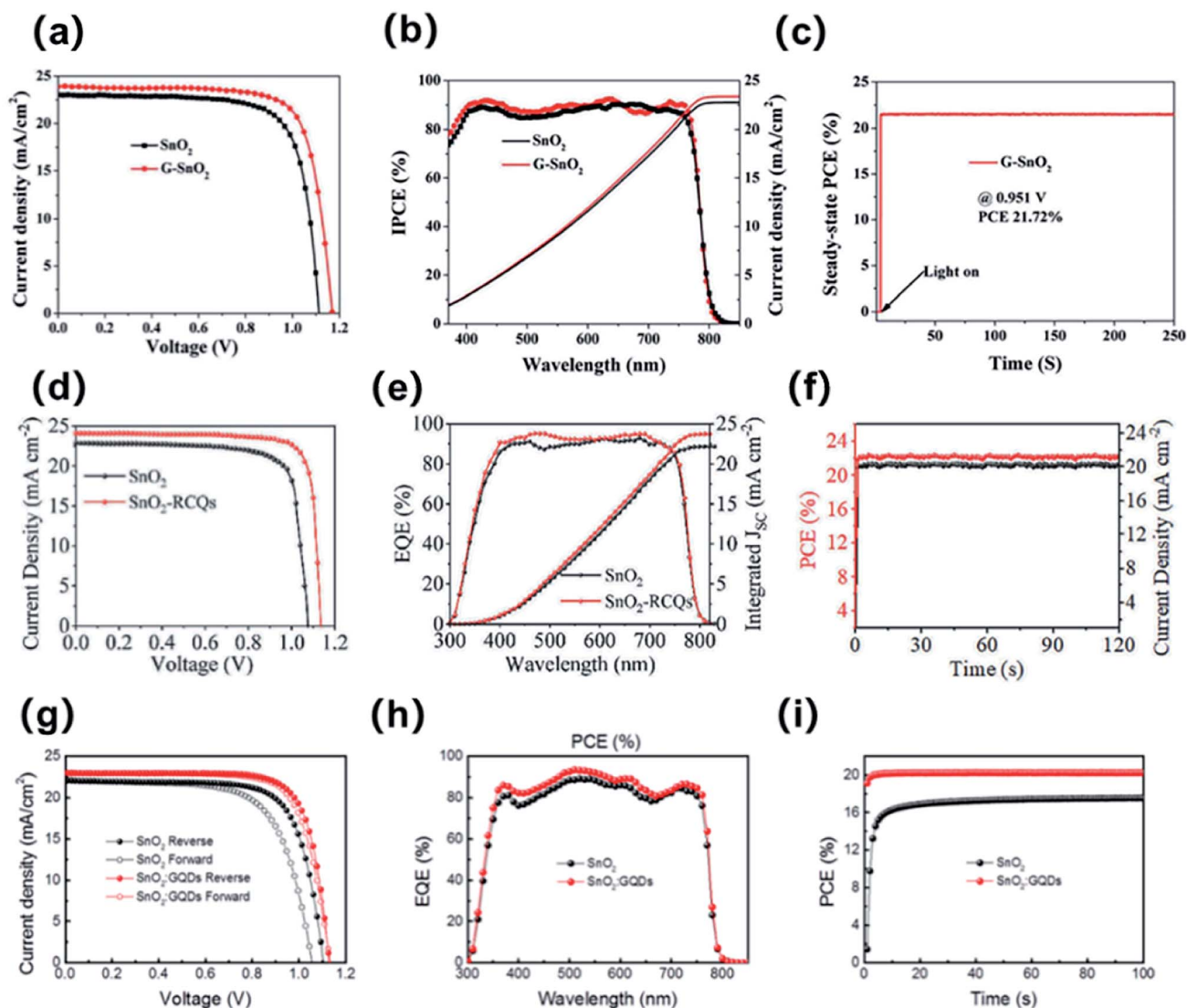


Fig. 12 *J*-*V* curves of perovskite solar cells based on (a) pristine and g-C<sub>3</sub>N<sub>4</sub> QD-treated SnO<sub>2</sub> ETLs; (d) pristine and RCQ-treated SnO<sub>2</sub> ETLs; (g) pristine and G QD-treated SnO<sub>2</sub> ETLs. The corresponding IPCE spectra of (b) pristine and g-C<sub>3</sub>N<sub>4</sub> QD-treated SnO<sub>2</sub> ETLs; (e) pristine and RCQ-treated SnO<sub>2</sub> ETLs; and (h) pristine and GQD-treated SnO<sub>2</sub> ETLs. Steady efficiency at the maximum power point of (c) pristine and g-C<sub>3</sub>N<sub>4</sub> QD-treated SnO<sub>2</sub> ETLs; (f) pristine and RCQ-treated SnO<sub>2</sub> ETLs; (i) pristine and GQD-treated SnO<sub>2</sub> ETLs. (a-c) Reproduced with permission.<sup>276</sup> Copyright 2020, Royal Society of Chemistry. (d-f) Reproduced with permission.<sup>277</sup> Copyright 2020, Wiley-VCH. (g-i) Reproduced with permission.<sup>269</sup> Copyright 2017, ACS Publishing Group.

Recently, owing to chemical bonding, self-assembled monolayer (SAM) ordered arrays of organic molecules formed by the spontaneous absorption onto a surface of molecular constituents from a vapor or liquid phase, are introduced to modify the SnO<sub>2</sub> surface, which is beneficial to tuning the energy level, regulating the WF at the surface and promoting the charge collection.<sup>49,279–283</sup> Besides, SAMs can reduce the vacancies and crystal traps at the perovskite, resulting in high-quality films and improved performance and stability of PSCs.

Yan and co-workers reported a choline chloride SAM on the surface of SnO<sub>2</sub> (chol-SnO<sub>2</sub>) by chemically reacting with the perovskite film to eliminate oxygen vacancies at the interface and lengthen the carrier lifetime (Fig. 13a and d). Finally, the device based on SnO<sub>2</sub> modified by choline chloride achieved a champion photovoltaic performance of 18.90% with free-hysteresis and a high  $V_{oc}$  (1.145 V).<sup>284</sup>

Kim and co-workers employed 2-[carbamimidoyl(methyl)amino]acetic acid (creatine), one of the standard amino acids in the human body, on a SnO<sub>2</sub> layer (Fig. 13b and e). Given the chemical structure, creatine can anchor on the surface of SnO<sub>2</sub> by a carboxylic acid functional group and had high polarity, leading to an increase in the charge extraction efficiency. The formamidinium-based perovskite PSC with modified SnO<sub>2</sub> achieved the optimal efficiency of 22.1% and maintained 90% initial performance even after 50 days.<sup>285</sup>

Anizelli and co-workers performed a systematic study of the application of two special SAMs, ethylphosphonic acid (EPA) and 4-bromobenzoic acid (BBA), onto SnO<sub>2</sub> and the NiO<sub>2</sub> ETL for stability. A series of stability tests of films and devices with and without SAM layers, at a working-condition temperature of 75 °C and continuous illumination, were designed. They demonstrated

a distinct evolution of perovskite thin films with irradiation time by adopting SAMs, and SAMs also generated several changes in the photoelectric parameters of the devices in view of their chemical properties and their combination with the SnO<sub>2</sub> and NiO<sub>2</sub> layers. At last, SAMs exhibited a significant effect on the lifetime of PSCs, extending up to five times that of the device's T50% (time for the efficiency to reach half of its initial value) in some cases.<sup>286</sup>

Hysteresis and degradation occurring in traditional PSCs structures with SnO<sub>2</sub> as the ETL has not been well understood. Tumen-Ulzii and co-workers modified the SnO<sub>2</sub> surface by a C<sub>60</sub> pyrrolidine tris-acid (CPTA) SAM because of the ability to form a strong chemical interaction with the SnO<sub>2</sub> surface (Fig. 13c and f). Furthermore, the SAM can effectively deactivate these hydroxyl groups, which localized the positive ions, leading to the hysteresis and degradation in PSCs. After surface treatment, they obtained free-hysteresis and long-term stability PSCs with no degradation after 1000 h of continuous light incidence.<sup>287</sup> Although PCBM or the C<sub>60</sub> buffering layer has the merits of suppressing hysteresis behavior and reducing the interfacial charge recombination loss, we do not ignore the drawbacks of difficulties in depositing them. For buffering layers, thermal deposition can precisely control its thickness, but it takes more cost and energy consumption to deposit them in a vacuum environment. On the other hand, solvent orthogonality is required to be solved because the polar solvents used in perovskite precursors like dimethylformamide (DMF) and dimethyl sulphoxide (DMSO) destroy the perovskite crystal structures.

**4.3.4 Two-dimensional materials.** Recently, two-dimensional (2D) materials such as graphene, MXenes, and metal sulfides have been commonly introduced into SnO<sub>2</sub> based on PSCs owing to their unique photoelectric

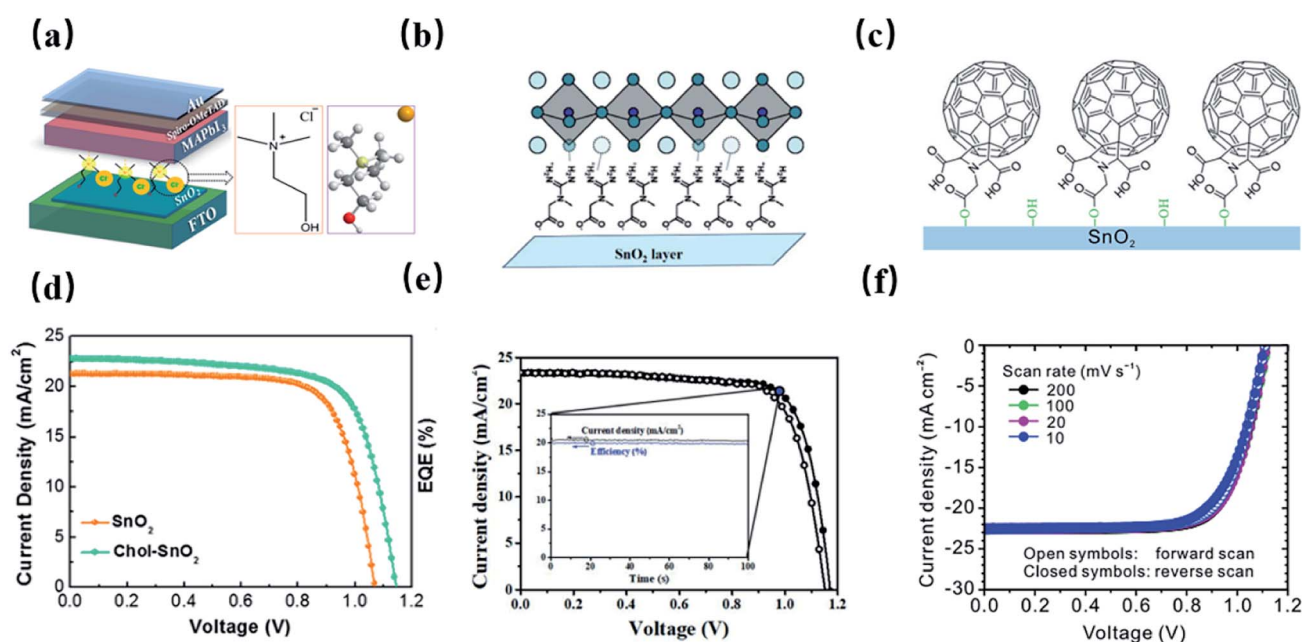


Fig. 13 Schematic illustration of the formation of various self-assembled monolayers adhering to SnO<sub>2</sub> layers and  $J$ - $V$  curve of devices with different SAM treatments. (a and d) Choline chloride treatment. Reproduced with permission.<sup>284</sup> Copyright 2020, ACS Publishing Group. (b and e) 2-[Carbamimidoyl(methyl)amino] acetic acid treatment. Reproduced with permission.<sup>285</sup> Copyright 2015, Royal Society of Chemistry. (c and f) C<sub>60</sub>-pyrrolidine tris-acid treatment. Reproduced with permission.<sup>287</sup> Copyright 2020, Nature Publishing Group.

properties.<sup>72,77,288–291</sup> MXenes are promising 2D materials that process high electron mobility and less light absorption in the visible range. Their general chemical formula is  $M_{n+1}X_nT_x$ , in which M displays a type of early transition metal, X usually is a carbon and/or a nitrogen atom, and T is the surface termination group (usually oxygen- and/or fluorine-containing groups).<sup>292–294</sup> Interestingly, the application of MXenes has been reported in PSCs as additives in the perovskite layer and ETLs.<sup>291,295,296</sup>

Wang and co-workers used  $Ti_3C_2T_x$  MXene to increase the conductivity and the charge collection ability of the  $SnO_2$  ETL. The MXene-modified  $SnO_2$  ETL also led to a preferable growth of perovskite films with free defects. Consequently, the PSCs obtained the best photovoltaic performance of 20.65% with minimal hysteresis.<sup>290</sup>

Yang and co-workers introduced  $Ti_3C_2$  (the most widely studied MXene) nanosheets into  $SnO_2$  precursors to increase the ETL conductivity *via* a low-temperature method (Fig. 14a, b and c). Through optimizing the  $Ti_3C_2$  contents, the device with the perovskite film of  $MAPbI_3$  obtained 18.34%, which was much higher than that of only  $SnO_2$ -based PSCs. The enhancement of the PCE can be ascribed to good bandgap alignment, leading to faster charge extraction from the perovskite layer.<sup>291</sup>

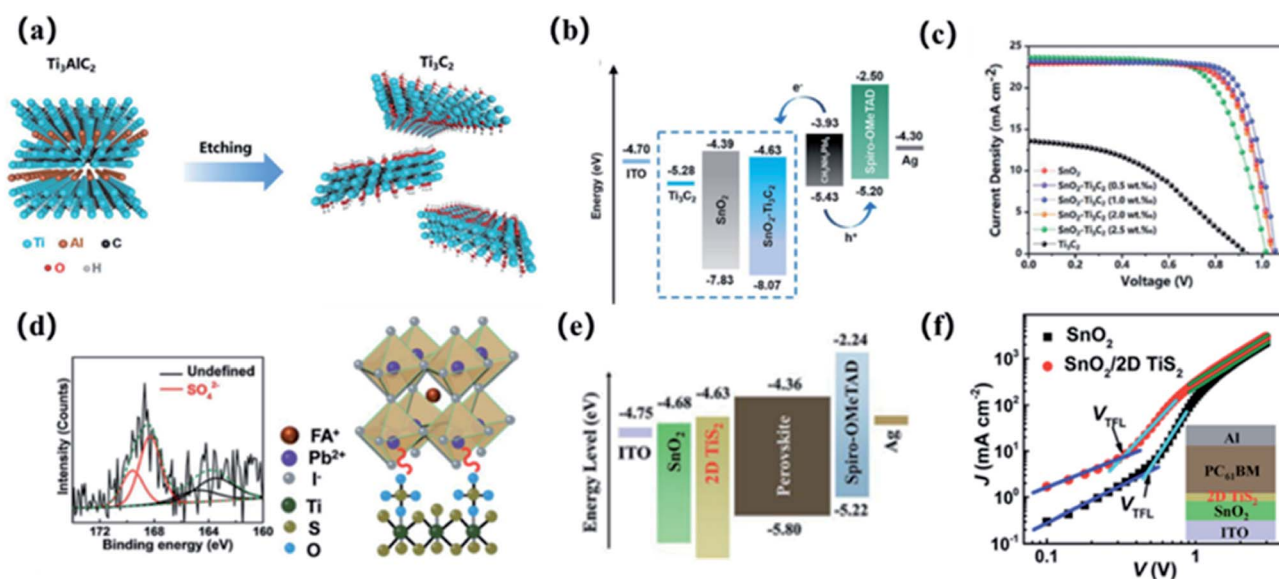
Some metal sulfide materials are also good choices to modify the  $SnO_2$  for enhanced electron conductivity. Huang and co-workers spin-coated the 2D  $TiS_2$  layer on the top of  $SnO_2$  as a bilayer ETL (Fig. 14d, e and f). 2D  $TiS_2$  can suppress trap sites of  $SnO_2$  and change the energy level alignment, resulting in improved electron mobility. The highest PCE reached was 21.73% with free hysteresis.<sup>288</sup>

**4.3.5 Carbon materials.** Carbon-based materials are suitable charge-transfer materials for commercializing large-scale

PSCs due to low-expense, high electron conduction, especially low-temperature fabrication (100 °C),<sup>297,298</sup> and similar work function as gold (5.0 and 5.1 eV, respectively).<sup>297</sup> Besides, they possess a highly hydrophobic nature, which protect moisture infiltration into the perovskite layer, resulting in long-term stability without encapsulation.<sup>299</sup> Nowadays, carbon-based materials including graphene, carbon nanotubes (CNTs), and carbon or graphene nanodots are widely used in PSCs as additives in perovskite precursors, interlayers between ETL or HTL with the perovskite layer and cathode.<sup>300–305</sup>

Tang and co-workers prepared  $SnO_2$  and carbon nanotubes (CNTs) hybrid ETL ( $SnO_2$ -CNT) by spin-coating method.<sup>116</sup> Besides, carbon nanotubes (CNTs) were modified by oxidative treatment and then dispersed well in  $SnCl_4 \cdot 5H_2O$  solution (Fig. 15a and b). As a consequence, the best PCE of 20.33% was obtained with negligible hysteresis, which was attributed to the significant increase in the conductivity of  $SnO_2$  films and decrease in the trap-state density of  $SnO_2$  films. Wang and co-workers firstly introduced carbon nanodots (CNDs) into  $SnO_2$  ETLs by a facile solution method. CNDs could effectively reduce the defect density and promote electron mobility in  $SnO_2$ . Finally, the device with ITO/ $SnO_2$ : CNDs/perovskite/spiro-OMeTAD/Au structure obtained a high power conversion efficiency (PCE) of over 20% with free hysteresis. Additionally, the  $SnO_2$ : CNDs device dropped only 10% of the initial PCE after storage in ambient for 1200 h and showed better UV stability after continuous UV illumination.<sup>306</sup>

Zhang and co-workers firstly introduced graphdiyne (GDY) as a novel carbon material to optimize the charge collocation process of  $SnO_2$  ETL, tune the growth of perovskite and eliminate interfacial defects towards both perovskite crystallization process and subsequent photovoltaic service duration. Through



**Fig. 14** (a) Schematic diagram of  $Ti_3C_2$  formation. (b and e) Energy level diagram of the components in the semiconductor hybrid perovskite. (c) Backward scan  $J$ - $V$  curves of devices with a  $SnO_2$  ETL and with  $SnO_2$ - $Ti_3C_2$  ETLs at various  $Ti_3C_2$  concentrations. (d) High-resolution XPS spectra of S 2p on the  $SnO_2$ - $TiS_2$  film; working mechanism of 2D  $TiS_2$  interaction with the perovskite crystal; (f)  $J$ - $V$  curves of electron-only devices with the inset illustrating the device structure. (a–c) Reproduced with permission.<sup>288</sup> Copyright 2019, Royal Society of Chemistry. (d–f) Reproduced with permission.<sup>291</sup> Copyright 2019, Royal Society of Chemistry.

the GDY modification, the PCE of over 21% was achieved with 10% improvement together with free hysteresis. It is demonstrated that GDY treated SnO<sub>2</sub> layer improved electron mobility and more facilitated energy level alignment (Fig. 15c and d). Moreover, the improved interfacial hydrophobicity effectively

impeded excess heterogeneous perovskite nucleation, leading to the higher crystal grain size of perovskite, fewer grain boundaries, and decreased trap density.<sup>307</sup>

Zhao and co-workers treated SnO<sub>2</sub> nanocrystals by chemically modified graphene as ETL for highly efficient and stable

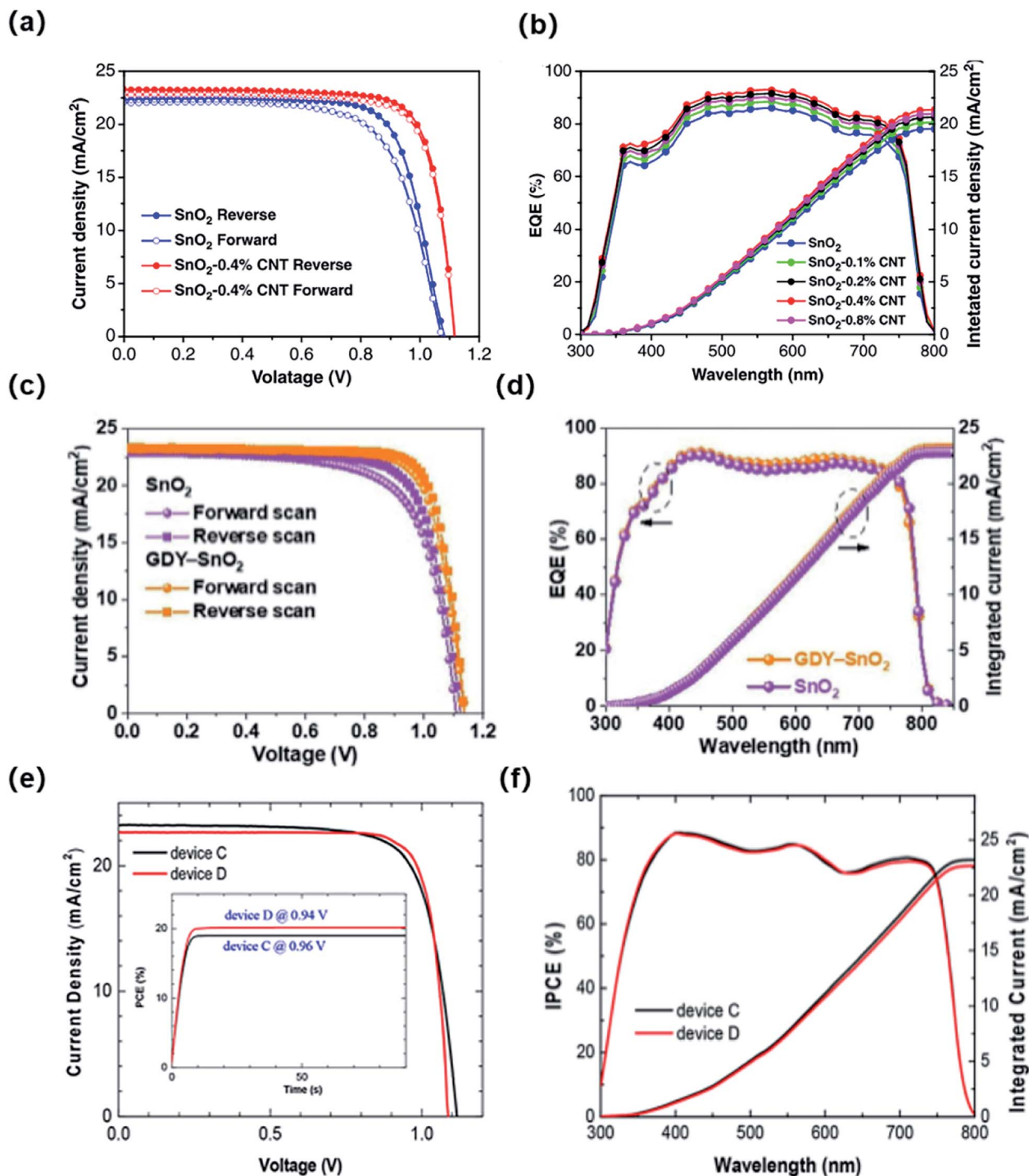


Fig. 15 J-V curves of (a) SnO<sub>2</sub> and CNT-SnO<sub>2</sub> ETLs; (c) SnO<sub>2</sub> and GDY-SnO<sub>2</sub> ETLs; (e) SnO<sub>2</sub> and graphene-SnO<sub>2</sub> ETLs. EQE spectra of (b) SnO<sub>2</sub> and CNT-SnO<sub>2</sub> ETLs. (d) SnO<sub>2</sub> and GDY-SnO<sub>2</sub> ETLs. (f) SnO<sub>2</sub> and graphene-SnO<sub>2</sub> ETLs. (a and b) Reproduced with permission.<sup>116</sup> Copyright 2020, Wiley-VCH. (c and d) Reproduced with permission.<sup>307</sup> Copyright 2020, Wiley-VCH. (e and f) Reproduced with permission.<sup>308</sup> Copyright 2018, ACS Publishing Group.

PSC (Fig. 15e and f). Besides, they also reported a creative strategy to disperse graphene in an aqueous solution that can preserve any residue on the SnO<sub>2</sub> film. Finally, the best device showed a PCE of over 20% with a high fill factor of up to 82%, which resulted from the enhanced conductivity (Table 4).<sup>308</sup>

## 5. Hysteresis and stability

The severe hysteresis and inferiority in the stability of PSCs under operation conditions are urgent challenges that quietly inhibit the PSCs from being used in the commercialization of laboratory products.

### 5.1 Hysteresis suppression

The presence and behavior of hysteresis, the difference in the  $I$ - $V$  curve from the reverse scan (open-circuit to short-circuit) and the forward scan (short-circuit to open-circuit), is a fundamental problem in the perovskite solar cell field. This results in obstacles to the progress of the actual performance of the devices in operation. Compared with devices with an n-i-p structure with a scaffold and an inverted p-i-n structure with a fullerene ETL, PSCs with the regular planar structure show much more evidence of the hysteresis effect.

Although the reasons for the appearance of hysteresis in PSCs are not evident, energy defects at the interfaces, the grain boundary in the perovskite film, and capacitive and ferroelectric polarization possibly affect the hysteresis behavior.<sup>309–312</sup> Recently, it seems that hysteresis is induced by ion migration, which caused charge accumulation, unbalanced charge mobility, defects or traps in the instinct of perovskites and perovskite/ETL interfaces.<sup>313–317</sup> As mentioned above, various types of device structures exhibited different hysteresis behaviors. The contact between the perovskite and charge transport layers is the main factor within these other structures, suggesting that the contact could also influence the hysteresis.<sup>318</sup>

Compared with many other metal oxides as ETLs, SnO<sub>2</sub> has the merits of a more bottomless conduction band, higher

conductivity, and electron mobility, which is beneficial to charge transfer from perovskite to ETL low charge accumulation at the interface. To date, devices based on the SnO<sub>2</sub> ETL in planar PSCs show a little hysteresis effect than many common metal oxides as ETLs, especially the TiO<sub>2</sub> ETL.<sup>319</sup> For PSCs with n-i-p planar structures, SnO<sub>2</sub> is an ideal electron transport material as the ETL to almost solve the hysteresis problem. As previously mentioned, SnO<sub>2</sub> combined with doped elements,<sup>320</sup> bilayers,<sup>247,321,322</sup> and interfacial engineering<sup>323,324</sup> can retard the formation of the defect states, which improve the carrier transport performance, leading to negligible hysteresis in the device.

Tumen-Ulzii and co-workers treated the SnO<sub>2</sub> surface with a self-assembled monolayer and achieved a hysteresis-free PCE over 18% (Fig. 16). It was found that hydroxyl groups existing at the SnO<sub>2</sub> surface induced positive ion localization, resulting in hysteresis and degradation. Interestingly, a self-assembled monolayer of a fullerene derivative (CPTA-SAM) can effectively deactivate these surface -OH groups. The temperature and scan speed can affect the hysteresis. Besides, with temperature increase or scan speed decrease, more significant hysteresis is apparent in  $J$ - $V$  curves. PSCs with CPTA-SAM treatment significantly reduced the  $J$ - $V$  hysteresis of PSCs at different scan speeds in contrast to devices without CPTA-SAM treatment. Furthermore, negligible hysteresis was observed in PSCs with the CPTA-SAM even at a high temperature of 60 °C.<sup>287</sup>

Ye and co-workers spin-coated KCl and NaCl on the SnO<sub>2</sub> surface to suppress the hysteresis in flexible PSCs.<sup>325</sup> The KCl and NaCl treatments effectively improve the power output of flexible PSCs. However, devices with NaCl modification showed a profound hysteresis effect in  $J$ - $V$  curves. It suggested that the hysteresis relied strongly on alkali metals. With the increase of the ionic radius of alkali metal ions from Li<sup>+</sup> to K<sup>+</sup> and then to Cs<sup>+</sup>, the hysteresis effect first gradually decreased and disappeared, and then appeared again and increased, which was strongly related to the trapping density.<sup>326,327</sup> In addition, it can reduce the device hysteresis to use a suitable SnO<sub>2</sub> fabrication process such as ALD, CBD, *etc.*

Table 4 Representative PSCs with interface modification

|                  | Passivation materials                         | $J_{sc}$ (mA cm <sup>-2</sup> ) | $V_{oc}$ (V) | FF (%) | PCE (%) | Ref. |
|------------------|---|---------------------------------|--------------|--------|---------|------|
| Ammonium salts   | Girard's reagent T                            | 22.92                           | 1.146        | 82.3   | 21.63   | 97   |
| Ammonium salts   | NH <sub>4</sub> F                             | 24.60                           | 1.16         | 81.4   | 23.2    | 272  |
| Ammonium salts   | N(CH <sub>3</sub> ) <sub>4</sub> OH           | 22.51                           | 1.14         | 79     | 20.28   | 273  |
| Ammonium salts   | EDTA  | 24.57                           | 1.11         | 79.2   | 21.6    | 274  |
| QDs              | g-C <sub>3</sub> N <sub>4</sub>               | 23.03                           | 1.176        | 78.3   | 22.13   | 276  |
| QDs              | RCQ   | 24.10                           | 1.14         | 83     | 22.77   | 277  |
| QDs              | GQD   | 23.05                           | 1.134        | 77.8   | 20.31   | 269  |
| SAMs             | Choline chloride                              | 22.80                           | 1.145        | 72.41  | 18.90   | 284  |
| SAMs             | Creatine                                      | 23.4                            | 1.19         | 75.9   | 20.8    | 285  |
| 2D materials     | Ti <sub>3</sub> C <sub>2</sub> T <sub>x</sub> | 24.34                           | 1.11         | 76.4   | 20.65   | 290  |
| 2D materials     | Ti <sub>3</sub> C <sub>2</sub>                | 23.14                           | 1.06         | 75     | 18.34   | 291  |
| 2D materials     | TiS <sub>2</sub>                              | 24.57                           | 1.11         | 79.4   | 21.73   | 288  |
| Carbon materials | CNDs  | 23.26                           | 1.12         | 78.23  | 20.33   | 116  |
| Carbon materials | CNDs  | 23.14                           | 1.10         | 79     | 20.03   | 306  |
| Carbon materials | Graphdiyne                                    | 23.32                           | 1.137        | 79.62  | 21.11   | 307  |
| Carbon materials | Graphene                                      | 22.66                           | 1.084        | 82.1   | 20.16   | 308  |

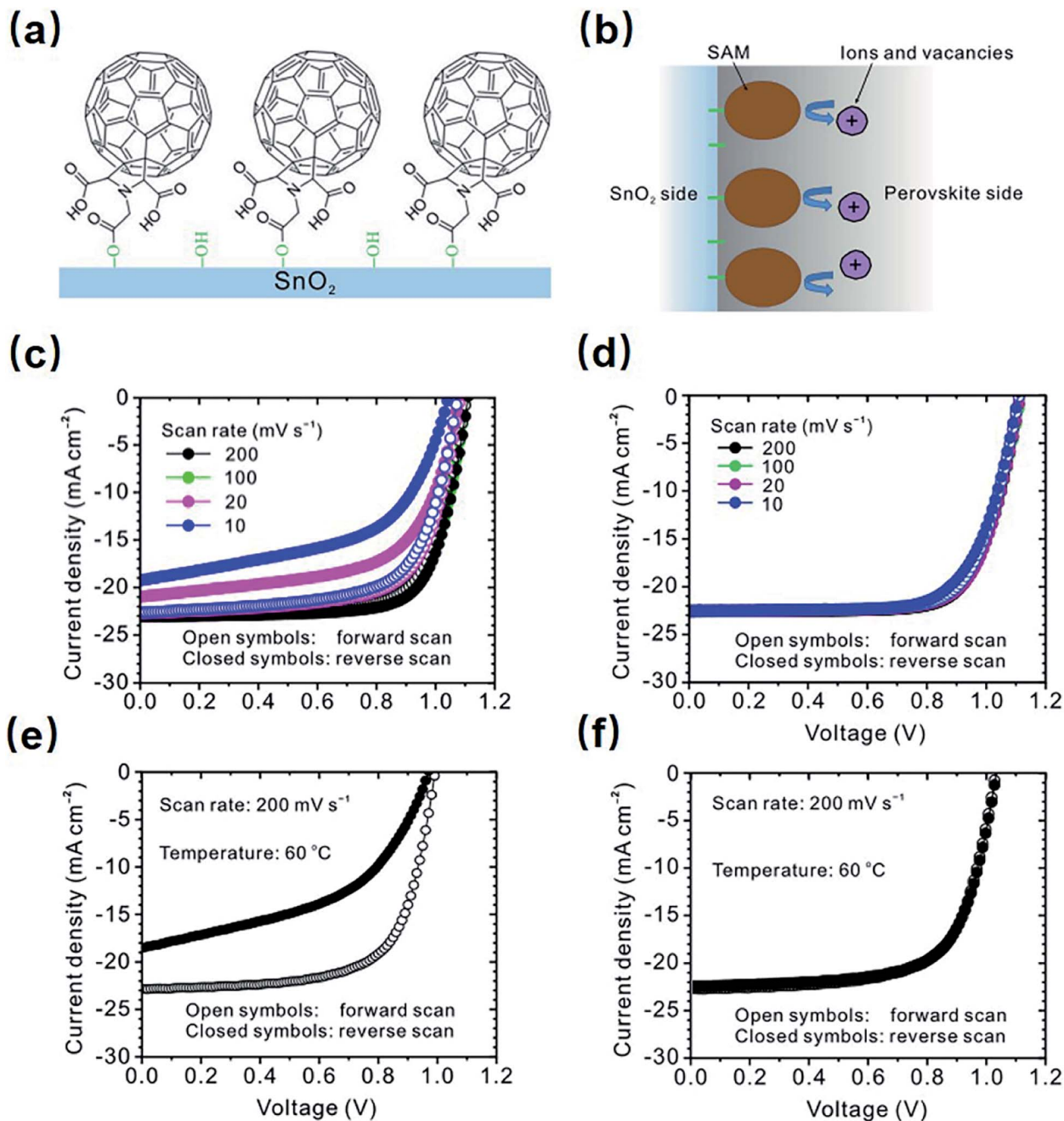


Fig. 16 Positive effect of using a self-assembled monolayer (SAM) on the hysteresis and carrier recombination characteristics in perovskite solar cells. (a) Mixed self-assembled monolayers adhering to the SnO<sub>2</sub> substrates and (b) schematic illustration of reducing localized ionic charges by eliminating -OH groups on the surface; backward and forward scan  $J$ - $V$  curves at different scan speeds: (c) untreated devices and (d) devices with SAM treatment; backward and forward scan  $J$ - $V$  curves measured at a fast scan rate of 200 mV s<sup>-1</sup> at 60 °C: (e) untreated devices and (f) devices with SAM treatment. Reproduced with permission.<sup>287</sup> Copyright 2020, Nature Publishing Group.

## 5.2 Device stability

**5.2.1 Ambient stability.** SnO<sub>2</sub> is more stable in oxygen and moisture than TiO<sub>2</sub>, an ideal alternative to the TiO<sub>2</sub> ETL for device stability.<sup>188,328,329</sup> Zhang and co-workers found that using poly(vinylpyrrolidone)-doped SnO<sub>2</sub> as the ETL, 88% of its highest PCE is retained even after 41 days of storage without encapsulation.<sup>330</sup> Huang and co-workers also revealed that the SnO<sub>2</sub> ETL modified with polymer ethoxylated polyethylenimine

(PEIE) indicated significant storage device stability, and the device with SnO<sub>2</sub>:PEIE ETL preserved 82.1% of its original PCE (PCE<sub>1/4</sub>, 16.89%) after 70 days of storage.<sup>331</sup> Wang and co-workers designed TiO<sub>2</sub>/SnO<sub>2</sub> bilayer as the ETL in CsPbI<sub>2</sub>Br all-inorganic perovskite, and the devices showed superior photovoltaic properties, particularly excellent phase and thermal stability. After one month of storage in an N<sub>2</sub> environment without any encapsulation, the PCE can retain about 95% of the original efficiency (Fig. 17a and b).<sup>332</sup>

Apart from  $\text{SnO}_2$  as ETLs in regular structures,  $\text{SnO}_2$  can be introduced as a protecting layer on the top of the perovskite layer or fullerene layer.<sup>87,127,265,333,334</sup> Wang and co-workers used  $\text{SnO}_2$  nanocrystals combined with  $\text{HClO}_4$  and  $\text{HCl}$  treatment as a buffer layer, inserting it into the  $\text{C}_{60}/\text{Ag}$  electrode interface (Fig. 17c and d). The devices with the  $\text{HClO}_4$ - $\text{SnO}_2$  ETL without encapsulation increased the PCE up to 16.36% with almost negligible hysteresis and maintained over 80% of their highest PCE after storage in open air for 90 days (>2100 h) and reduced by only about 20% its initial efficiency after 41 h under heating at 85 °C.<sup>263</sup>

**5.2.2 Light illumination stability.**  $\text{TiO}_2$  is a common metallic oxide used as the ETL, which induces decomposition of PSC under UV illumination owing to their photocatalytic activity. Due to the efficiency and stability degradation, there is a mass of oxygen vacancies in the  $\text{TiO}_2$  lattice, which can be generated by UV illumination.<sup>200</sup> The oxygen vacancies cause deep trap states, interacting with molecular oxygen in ambient air, and then cause deep trap sites, which can interact with molecular oxygen in the environment by adsorption, leading to their passivation.<sup>41,335,336</sup> When deep traps are excited by oxygen desorption, the charge recombination easily occurs at the interface, resulting in a PCE loss. Besides,  $\text{TiO}_2$  is able to obtain excess electrons from perovskite because of its high

photochemical activity, which can cause photo-decomposition of the perovskite crystals, particularly in the humid environment.<sup>337–339</sup>

Liu and co-workers studied the reasons for the degradation process of the perovskite layer deposited on different ETLs ( $\text{PCBM}$ ,  $\text{TiO}_2$ , and  $\text{SnO}_2$ ) under strong ultraviolet irradiation. Although the  $\text{SnO}_2$  layer reduced light-induced chemical activity in contrast to the  $\text{TiO}_2$  layer, the serious decomposition of perovskite observed at the perovskite/ $\text{SnO}_2$  interface, together with the formation of hole structures, decreases the carrier transfer at the interface, owing to the separation of the perovskite absorber from ETLs and thus rapidly decreased the device performance (Fig. 18b).<sup>340</sup> Wang and co-workers used carbon nanodots (CNDs) to dope  $\text{SnO}_2$  as the ETL and found that  $\text{SnO}_2$ :CNDs based PSCs achieved an efficiency over 20% with nearly free hysteresis and maintained over 90% of the initial PCE in a  $\text{N}_2$  atmosphere for 1200 h and showed better UV stability under UV illumination for 200 h.<sup>306</sup>

Similarly, Abate and co-workers reported that Ga doping could improve UV-resistant mesoporous  $\text{SnO}_2$ . When  $\text{SnO}_2$  and  $\text{TiO}_2$  based PSCs were exposed to continuous light illumination for 1000 h, both devices exhibited a rapid decrease to 80% in the first 100 h (Fig. 18a). After this,  $\text{SnO}_2$  based PSCs retained

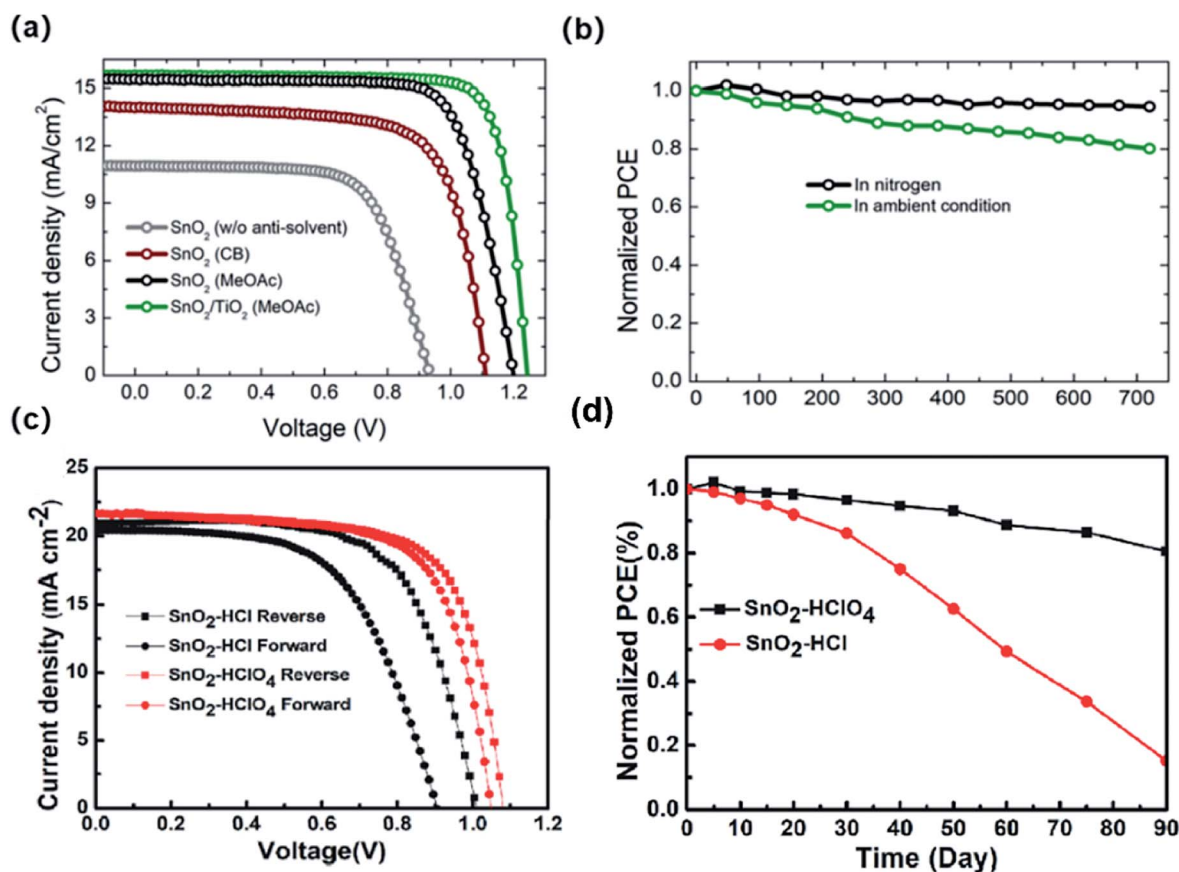


Fig. 17 *J*-*V* curves of devices based on (a)  $\text{SnO}_2$  and  $\text{TiO}_2/\text{SnO}_2$  ETLs and (c)  $\text{HCl-SnO}_2$  and  $\text{HClO}_4\text{-SnO}_2$  ETLs. Stability test of devices on (b)  $\text{SnO}_2$  and  $\text{TiO}_2/\text{SnO}_2$  ETLs in an  $\text{N}_2$  - filled glovebox and under ambient conditions (@R.T., 20–30% relative humidity) (d)  $\text{HCl-SnO}_2$  and  $\text{HClO}_4\text{-SnO}_2$  ETLs under the humidity of 55% ± 10% at 85 °C in open air. (a and b) Reproduced with permission.<sup>332</sup> Copyright 2020, ACS Publishing Group. (c and d) Reproduced with permission.<sup>263</sup> Copyright 2020, Elsevier.



around 70% of the original efficiency up to 1000 h of full-spectrum illumination. In contrast, the normalized PCE of TiO<sub>2</sub> based PSCs dropped rapidly and stabilized only 20% of the initial PCE after illumination.<sup>339</sup>

Wang and co-workers introduced a chlorine-rich perovskite interlayer (CIMPI) to modify the SnO<sub>2</sub> ETL/perovskite interface through halide exchange to improve the interfacial charge transfer (Fig. 18c). Encouragingly, the CIMPI-based PSC still maintained over 82% of the initial PCE under UV exposure with a high power of 100 mW cm<sup>-2</sup> after 500 h.<sup>341</sup>

More encouragingly, Gratzel and co-workers designed a bilayer ETL of an amorphous SnO<sub>2</sub> coated TiO<sub>2</sub> scaffold (mp-TiO<sub>2</sub>) layer, and they displayed that the devices with a TiO<sub>2</sub>/SnO<sub>2</sub> bilayer ETL rendered them more resistant to UV light than devices with only mp-TiO<sub>2</sub> as a single ETL (Fig. 18d).<sup>342</sup>

**5.2.3 Heat stability.** In addition to light and humidity, thermal treatment is also the cause of poor stability problems of perovskite solar cells. The temperature of the cells can increase under exposure to sunlight, resulting in accelerated degradation, especially for MA-based perovskite solar cells.<sup>343</sup> Some strategies were reported, such as designing 2D/3D heterojunctions, using a green antisolvent, interface engineering, and additive engineering for SnO<sub>2</sub>-based perovskite solar cells.<sup>344–350</sup>

Chen and coworkers deposited 4-imidazoleacetic acid hydrochloride (ImACHCl) on the top of the SnO<sub>2</sub> film, leading to a chemical bridge between SnO<sub>2</sub> and perovskite through an ester bond with SnO<sub>2</sub> (Fig. 19a). As a result, ImACHCl could improve the perovskite crystallization, suppress the non-radiative recombination, and the promote carrier lifetime. Moreover, an unencapsulated device with ImACHCl-modified SnO<sub>2</sub> retained 90% of its initial after 40 h of aging at 80 °C, while PCE was degraded by 53% for the control device.<sup>344</sup>

Zhang and coworkers used ethyl acetate (EA) as a green antisolvent to control the perovskite crystallization process, resulting in smooth and dense perovskite films with free pinholes (Fig. 19b). In the ambient atmosphere, the unencapsulated device maintained about 85% of its initial PCE after more than 1900 h of storage. Meanwhile, the device also showed remarkable thermal stability, retaining 81.03% of the original PCE value at 100 °C for 10 h.<sup>349</sup>

Interface engineering between SnO<sub>2</sub> and the perovskite layer is a common way to improve thermal stability. Tian and coworkers synthesized 2,5-diphenyl C<sub>60</sub> fulleropyrrolidine (DPC<sub>60</sub>) as an interfacial layer between perovskite and SnO<sub>2</sub> in planar perovskite solar cells (PSCs) (Fig. 19c). As a result, PSCs modified with DPC<sub>60</sub> obtained a PCE of 20.4% with high reproducibility. Furthermore, the device retained 82% of its initial efficiency after 200 h of 1 sun continuous irradiation and thermal aging (55 ± 5 °C) due to the suppression of heterogeneous nucleation and improvement in the crystallinity of the perovskite film.<sup>348</sup> Similarly, Choi and coworkers exhibited a PCE of 21.43% by incorporation of SnO<sub>2</sub> with a zwitterionic compound (3-(1-pyridinio)-1-propane sulfonate), which led to improved PCE and thermal stability (Fig. 19d).<sup>345</sup>

## 6. Commercialization and applications

### 6.1 Flexible perovskite solar cells (FPSCs)

Because of their potential in portable electronics, flexible perovskite solar cells (FPSCs) have sparked widespread research interest. Because of their low-temperature processability, SnO<sub>2</sub> ETLs play a critical role in realizing highly efficient flexible PSCs.<sup>351–353</sup>

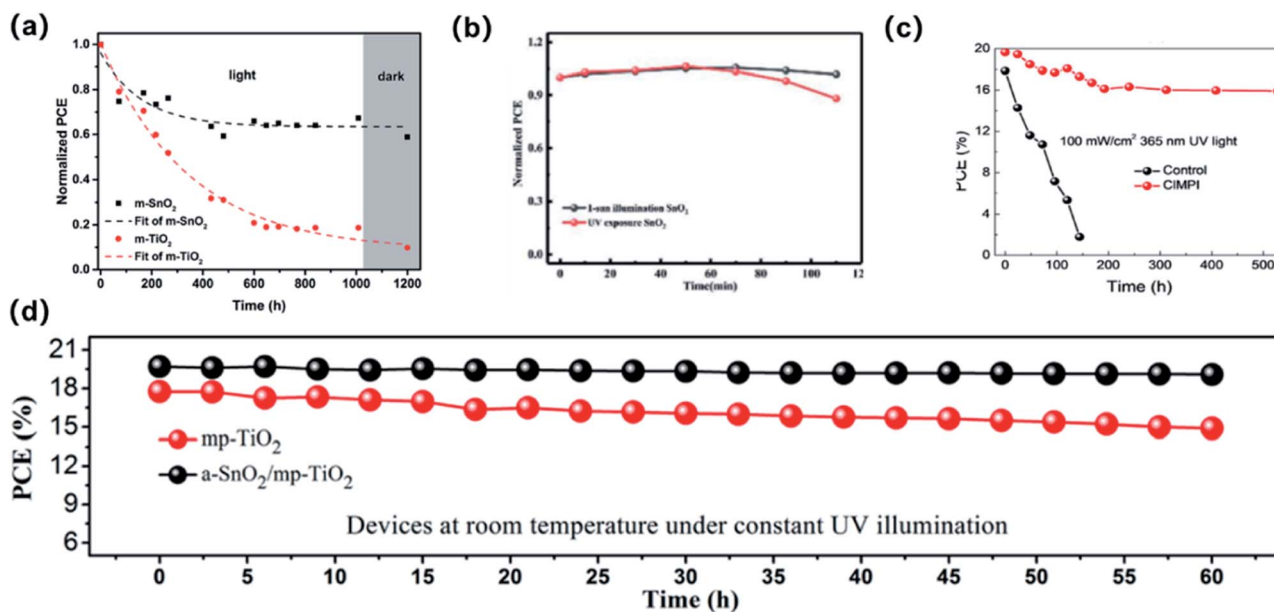


Fig. 18 UV light aging test of devices based on (a) *m*-SnO<sub>2</sub> and *m*-TiO<sub>2</sub> under 100 mW cm<sup>-2</sup> illumination in a N<sub>2</sub> atmosphere; reproduced with permission.<sup>339</sup> Copyright 2018, Royal Society of Chemistry. (b) *mp*-SnO<sub>2</sub> under one sun illumination and UV exposure in a N<sub>2</sub> atmosphere. Reproduced with permission.<sup>340</sup> Copyright 2020, Royal Society of Chemistry. (c) CIMPI-SnO<sub>2</sub> reproduced with permission.<sup>341</sup> Copyright 2019, Elsevier B.V. (d) *mp*-TiO<sub>2</sub> and SnO<sub>2</sub>/*mp*-TiO<sub>2</sub>. Reproduced with permission.<sup>342</sup> Copyright 2018, ACS Publishing Group.

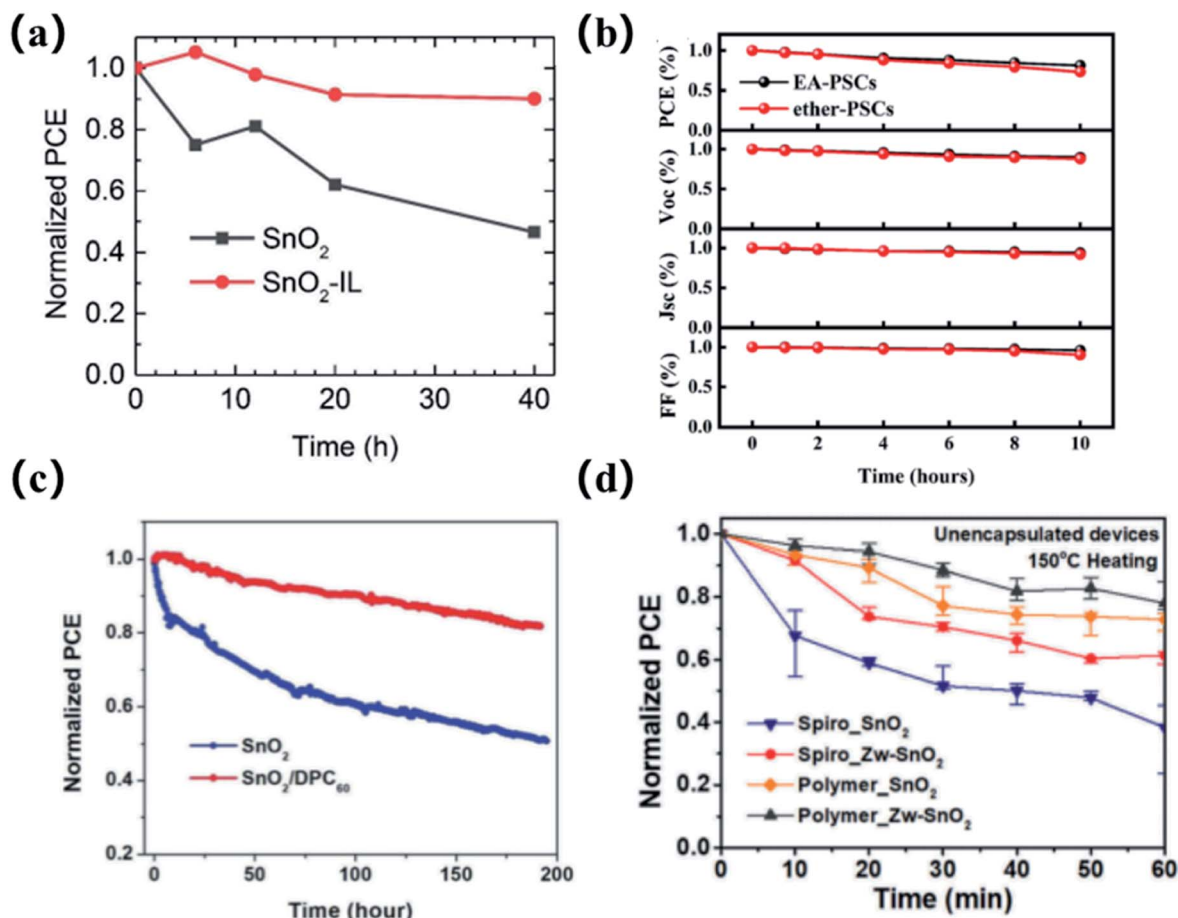


Fig. 19 Device thermal stability of (a) unencapsulated devices at 85 °C in the dark in the glovebox. Reproduced with permission.<sup>344</sup> Copyright 2019, Wiley-VCH. (b) Unencapsulated devices at 100 °C in air. Reproduced with permission.<sup>349</sup> Copyright 2020, Elsevier. (c) MPP tracking of the unencapsulated devices at (55 ± 5 °C) in a N<sub>2</sub> atmosphere. Reproduced with permission.<sup>348</sup> Copyright 2020, Wiley-VCH. (d) Unencapsulated devices at 150 °C in air. Reproduced with permission.<sup>345</sup> Copyright 2018, Royal Society of Chemistry.

Zhou *et al.* reported graphene quantum dots (GQDs)/SnO<sub>2</sub> composites (G@SnO<sub>2</sub>) as effective ETLs. GQDs can improve SnO<sub>2</sub> electron mobility and coverage. Furthermore, G@SnO<sub>2</sub> has a higher energy level than that of pristine SnO<sub>2</sub>, resulting in increased charge transfer and decreased charge recombination. As a result, the flexible PSCs based on G@SnO<sub>2</sub> ETLs achieved a champion PCE of 17.7% with exceptional mechanical durability, retaining more than 91% of the initial PCE value after 500 bending cycles with a bending radius of 7 mm.<sup>354</sup>

Wang *et al.* reported plasma-enhanced atomic layer deposition (PEALD) for SnO<sub>2</sub> ETLs processed at low temperatures. The PEALD-synthesized SnO<sub>2</sub> is postannealed at 100 °C in the presence of water vapor. Finally, the best flexible PSC demonstrated the highest reported efficiency of 18.36%.<sup>155</sup>

Dong *et al.* used ultraviolet ozone (UVO) pretreatment to introduce controlled trace amounts of surface absorbed water on the FTO or ITO for a full-coverage SnO<sub>2</sub> ETL with desirable morphology and crystallinity. It demonstrated optimal hydrolysis–condensation reactions for SnO<sub>2</sub> regrowth. Compared to the control SnO<sub>2</sub> ETL without UVO pretreatment, the rigid and flexible PSC devices with UVO pretreatment achieved high PCEs of up to 20.5% and 17.5%, respectively.<sup>355</sup>

However, the reported flexible PSCs are almost based on small surface areas to date. It is well known that low-temperature processable SnO<sub>2</sub> provides fundamental support for mass production *via* some scalable fabrication and coating techniques, with enormous potential for practical applications in light, wearable, and portable electronic devices.

## 6.2 Large-area perovskite solar cells

Large-area fabrication is a critical component in achieving industrial production and commercialization. In general, when the area of the devices is increased to a large scale, the PCE decreases due to the inevitable loss of homogeneity in the films. As a result, various scalable deposition methods and related morphology control strategies for large-area uniform SnO<sub>2</sub> films are developed, determining the performance of large-area flexible PSCs. A solution-based scalable deposition method appears to be promising for preparing large-area SnO<sub>2</sub> films. In the lab, spin-coating is the most commonly used method for producing PSCs; however, it is hard to use it in the large-area fabrication.<sup>356,357</sup> Other new methods for scalable production include slot-die,<sup>103</sup> spray-coating,<sup>358</sup> CBD,<sup>359,360</sup> sputtering,<sup>148,149</sup> and bar coating.<sup>361</sup>

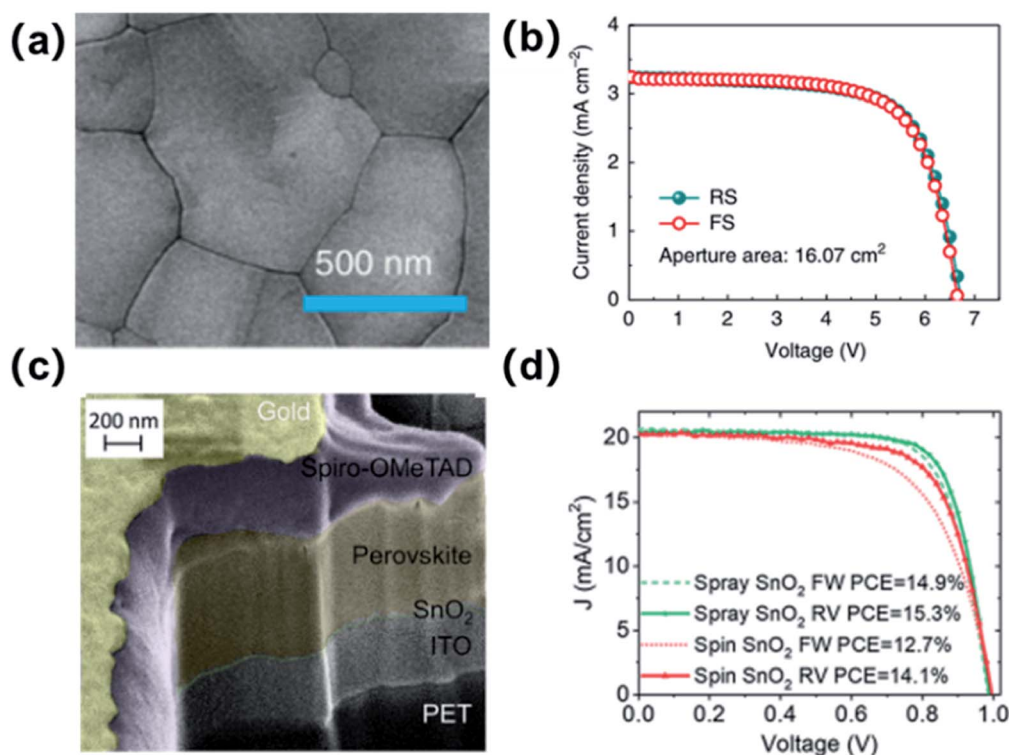


Fig. 20 Top view SEM images of (a) a perovskite film based on  $\text{SnO}_2$  fabricated by slot-die coating; (c) the cross-sectional SEM images of a perovskite solar cell based on  $\text{SnO}_2$  fabricated by spray-coating; forward/reverse scan  $J$ - $V$  curve of (b) the best device based on  $\text{SnO}_2$  fabricated by slot-die coating; (d) the best device based on  $\text{SnO}_2$  fabricated by spray-coating. (a and b) Reproduced with permission.<sup>103</sup> Copyright 2020, Nature Publishing Group; (c and d) Reproduced with permission.<sup>358</sup> Copyright 2021, ACS Publishing Group.

Bu *et al.* slot-die-coated  $\text{SnO}_2$  on  $5 \times 6 \text{ cm}^2$ -sized substrates with a potassium interfacial passivation strategy and achieved a 14.89% efficiency (Fig. 20a and b). The results demonstrated that potassium passivation could stabilize  $\text{SnO}_2$  colloids, reducing hysteresis in  $\text{SnO}_2$ -based devices.<sup>103</sup> Taheri *et al.* pioneered the concept of combining laser scribing optimization with automated spray-coating of  $\text{SnO}_2$  layers for FPSCs (Fig. 20c and d). The method produced uniform and dense  $\text{SnO}_2$  ETLs with PCEs of 12% and 10.7% with active areas of 16.84 and 21.2  $\text{cm}^2$ , respectively.<sup>358</sup> Qiu *et al.* looked into the effect of an oxidizing environment on the formation of  $\text{SnO}_2$  films. As an example, the champion device with an aperture area of 22.8  $\text{cm}^2$  demonstrated a PCE of 12.03%. Currently, the largest  $\text{SnO}_2$ -based PSC obtained by CBD deposition was 53.64  $\text{cm}^2$  (active area) on a 100  $\text{cm}^2$  substrate, with a certified PCE of 17.4%.<sup>360</sup>

The manufacturing cost of  $\text{SnO}_2$  films is an important parameter for scalable  $\text{SnO}_2$  fabrication. Appropriate deposition methods and raw materials can significantly reduce costs. Instability, on the other hand, can seriously shorten the device's lifespan. As a result, the optimized deposition methods, passivation strategies, and encapsulation have a high potential for scaling up PSCs.

## 7. Conclusions and outlook

$\text{SnO}_2$  has many merits of direct bandgap, high conductivity, low trap density, and being solution-processable under low-

temperature conditions, which has been regarded as an ideal electron transport material in the field of PSCs. So far, the champion efficiency of  $\text{SnO}_2$  ETL-based planar PSCs combined with passivation strategy has been increased to 25.2%, which approached the device with the mesoporous structure.

$\text{SnO}_2$ -based PSCs have distinctive device structures, including planar, mesoporous, distressed, and flexible substrate-based structures. Different testimony techniques for  $\text{SnO}_2$  to suit various structures have been reported. Although the annealing temperature is much lower than that of  $\text{TiO}_2$  preparation, it is still excessively high to flexible PSCs or inversed structure PSCs. Subsequently, loads of work should be promoted to bring down the process temperature and simplify the process.

Like other metal oxidation, pristine  $\text{SnO}_2$  films contain many bulk and surface defects. As previously mentioned  $\text{SnO}_2$  combined with doped elements, bilayers, and interfacial engineering can retard the formation of the defect states, which improves the carrier transport performance, leading to negligible hysteresis in the device. To guide the design of an efficient process, we need to fully characterize the types and density of defects that form in  $\text{SnO}_2$  and the followed perovskite to gain a fundamental understanding. In addition, standard characterization protocols should be established to properly evaluate the effect of interfacial modifiers on the performance and stability of PSCs. In principle, a molecular library could be found by investigating the effect of functional groups, the

conjugated system, and the substituent of the additives or interfacial modifiers on the passivation capacity. With the research information amassed and distributed in the entire exploration field, we can utilize AI to find the basic standards for choosing the materials and effective processes.

## Conflicts of interest

The authors declare no conflict of interest.

## Acknowledgements

This work was financially supported by the National Nature Science Foundation of China (21676188).

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